

Extending Proven Digital Verification Techniques for Mixed-Signal SoCs with VCS AMS

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Adiel Khan, Synopsys

Pierluigi Daglio, STMicroelectronics

Gernot Koch, Micronas

Agenda

This tutorial includes:

- Introduction to VCS AMS mixed-signal verification solution
- Technical presentation of AMS Testbench
- STMicroelectronics highlights their usage of VCS AMS to accelerate mixed-signal verification using Save and Restore
- Micronas describes their usage of VCS AMS behavioral modeling capabilities for their validation methodology of mixed-signal sensor-based applications.

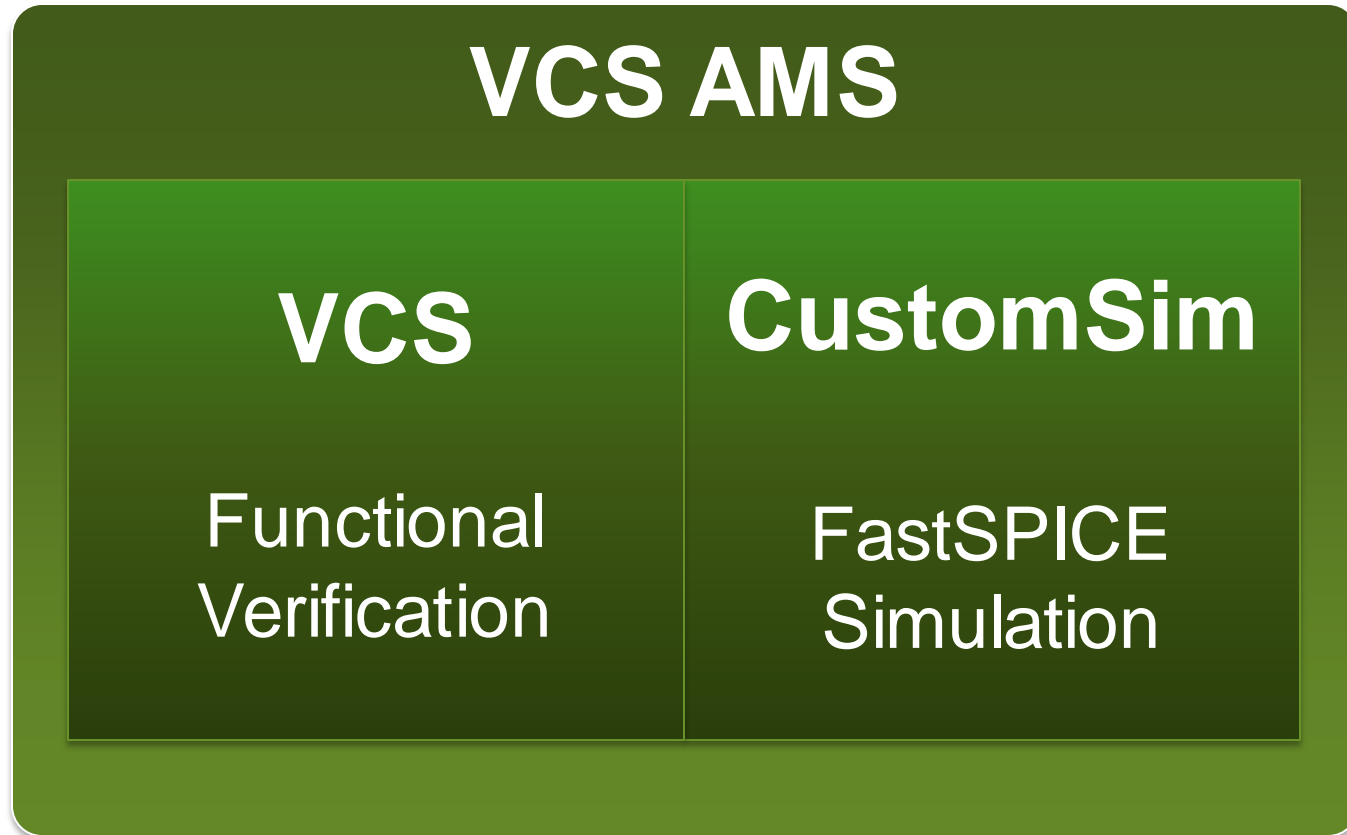
VCS AMS

Mixed-signal Verification Solution

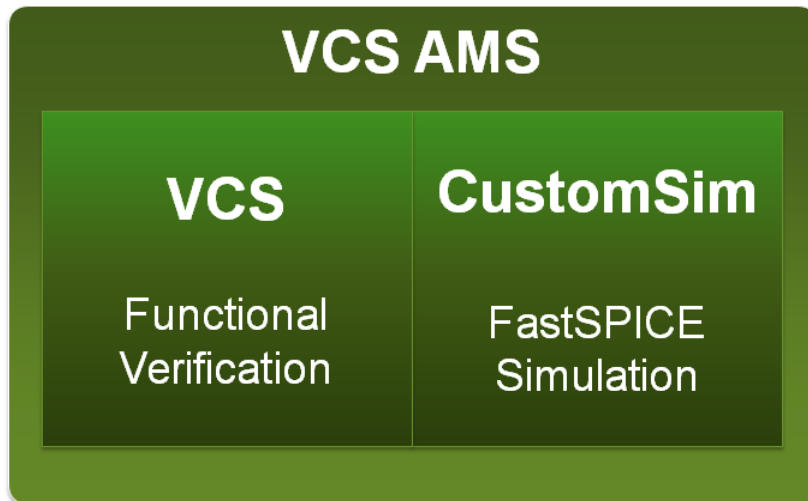
Helene Thibieroz
Product Marketing
Synopsys

Introducing VCS AMS

Mixed-signal Verification Solution



VCS AMS – Technologies



- Performance
- Flexibility
- Broad Languages
- Debug

New!

→ **AMS Testbench**

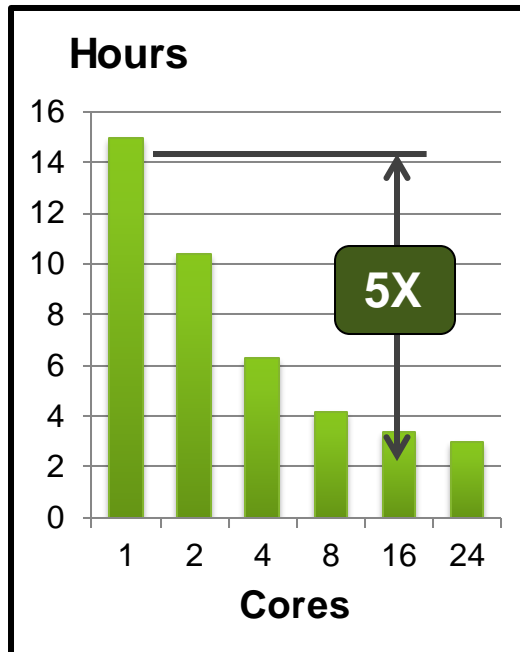
New!

→ **Native Low Power**

VCS AMS – Performance

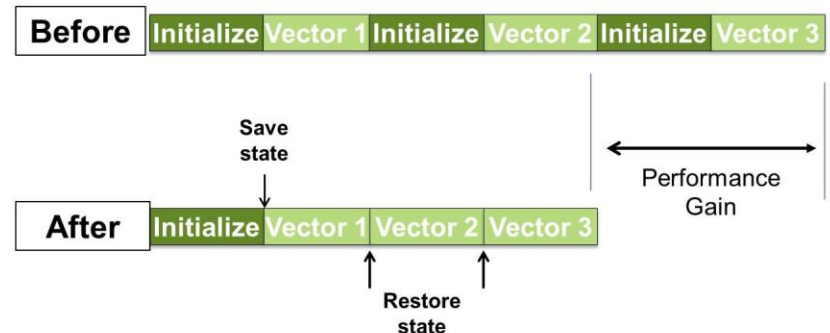
Best Performance with Transistor-level Accuracy

Multicore



15 hours to 3 hours
RF RX, 300K tx

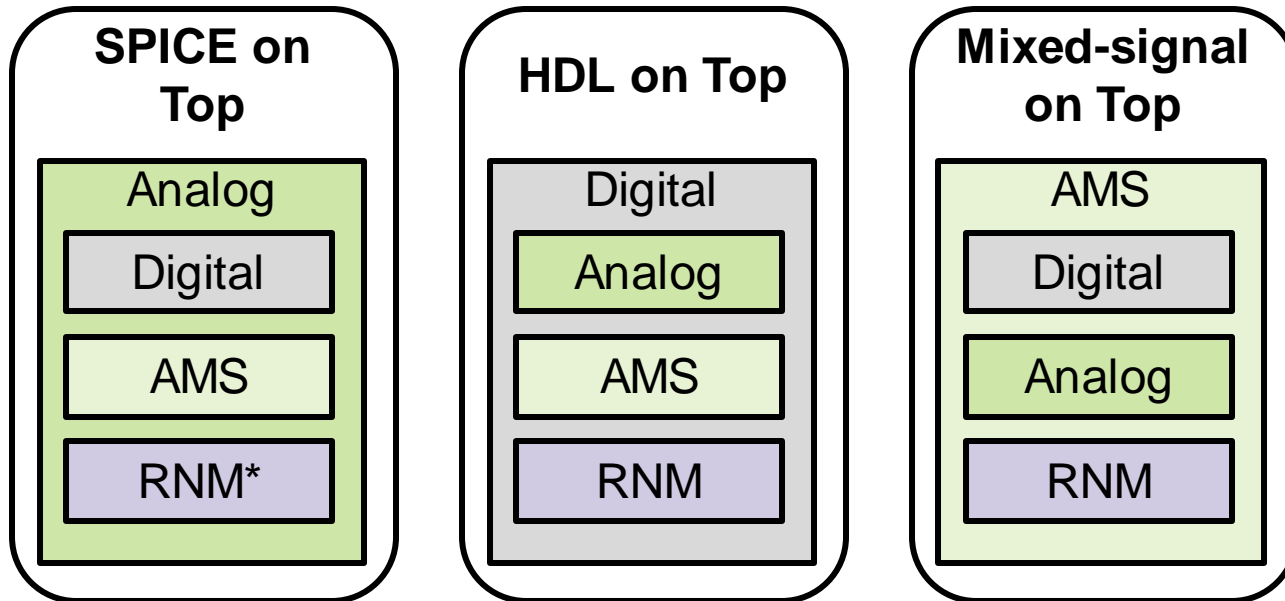
Save and Restore



**Enables Mixed-signal
Verification for Regression**

VCS AMS – Flexibility

Multiple Topologies Offered for Complex SoCs



Multiple Topologies and Configurations

* Real Number Modeling

VCS AMS – Broad Language Support

Enables Complex Integration Schemes for Mixed-signal SoCs

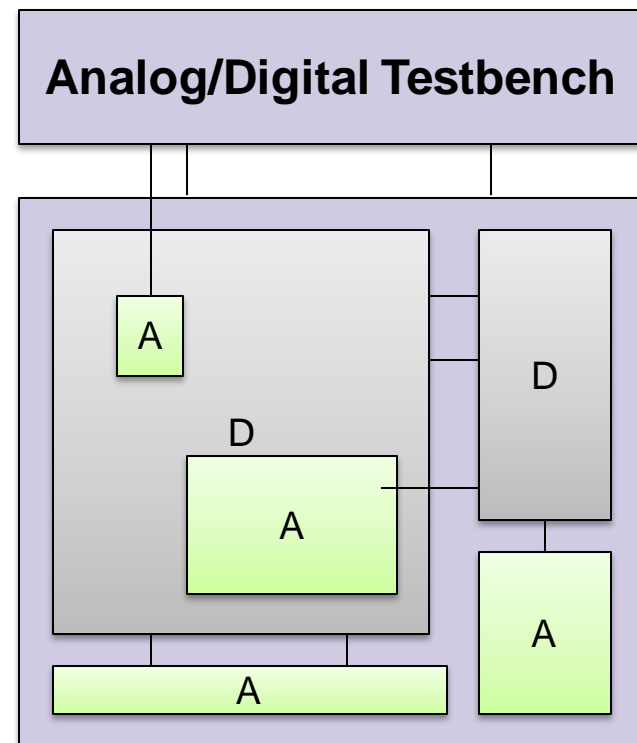
Analog	Digital	Mixed-signal
SPICE	Verilog	Verilog-AMS
Verilog-A	VHDL	Real Number Model
SPEF, DSPF, DPF	SystemVerilog	SystemVerilog nettype
	SystemC, Matlab	

VCS AMS – Debug

Assisted Setup and Debugging

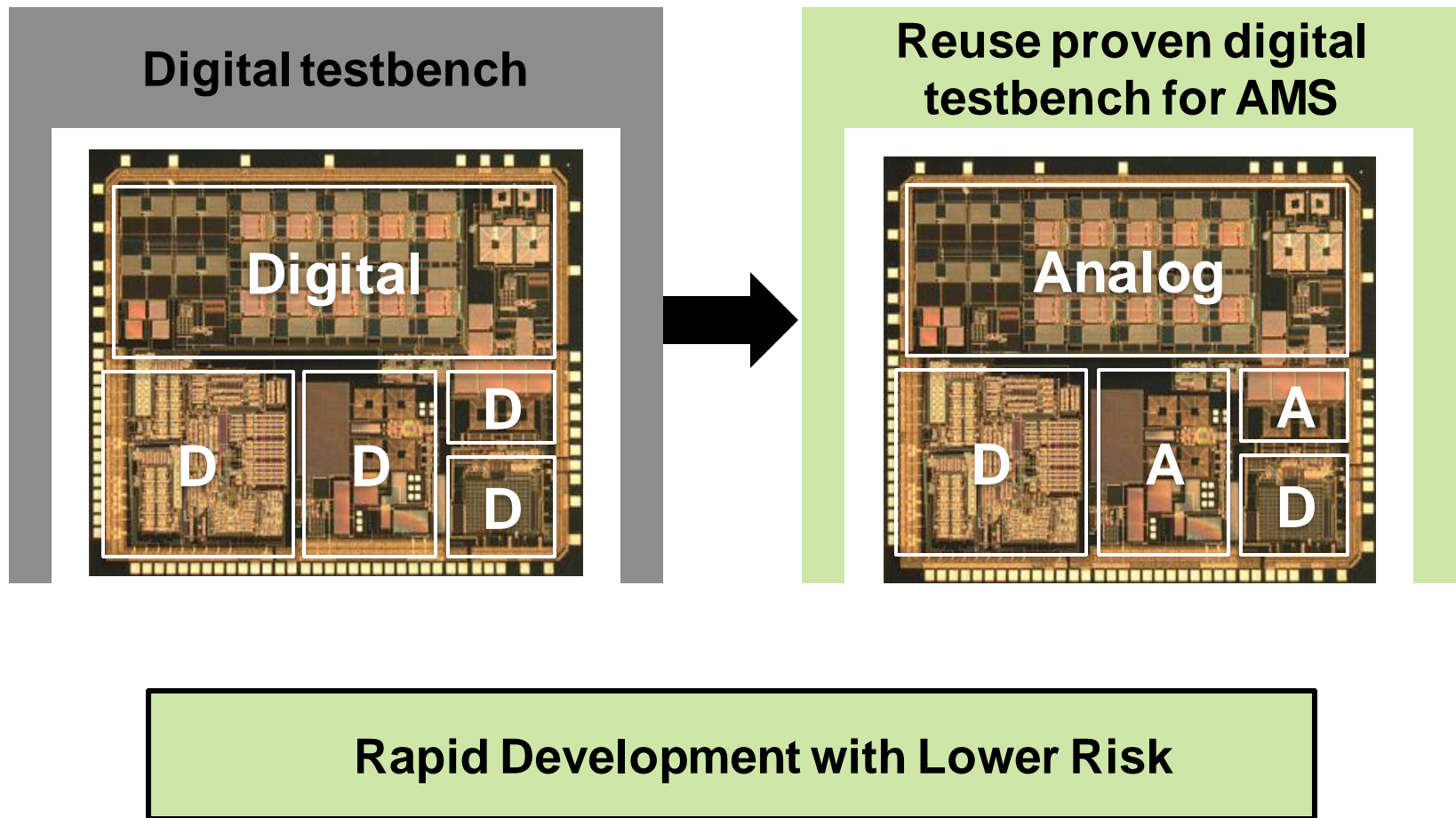
- Easy configuration
 - VCS use model
 - Netlist driven
- Automated insertion of A/D interface elements
 - Optimized for speed and accuracy
- Connectivity reports
 - Interface elements
 - Port mapping

Mixed-signal Testbench



VCS AMS – AMS Testbench

Expanding UVM Methodology for Analog

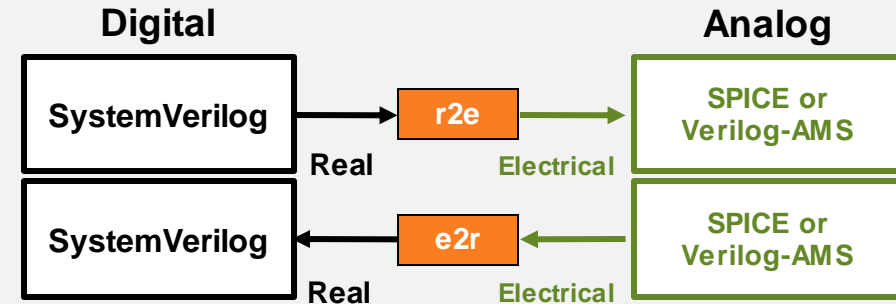


VCS AMS – AMS Testbench

Digital Verification Techniques for Mixed-signal SoCs

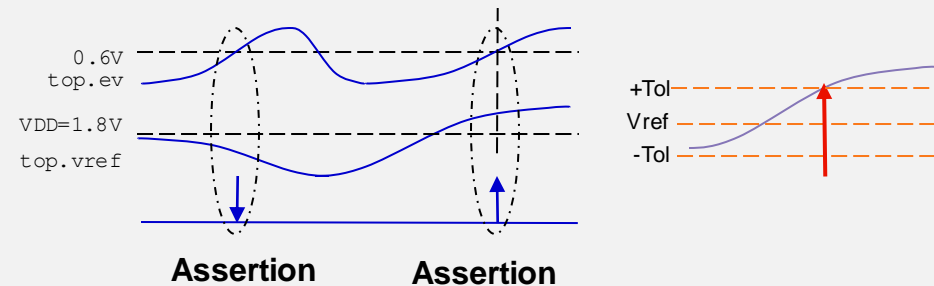
Connectivity

Electrical \Leftrightarrow Real conversion
Asynchronous analog events



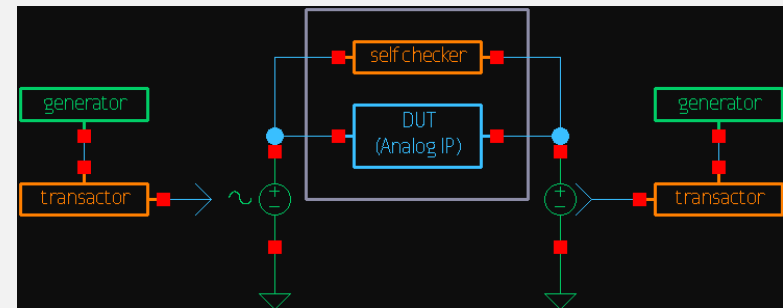
Metric-driven

AMS assertions
AMS constrained-random stimulus
AMS checkers
SystemVerilog real number modeling



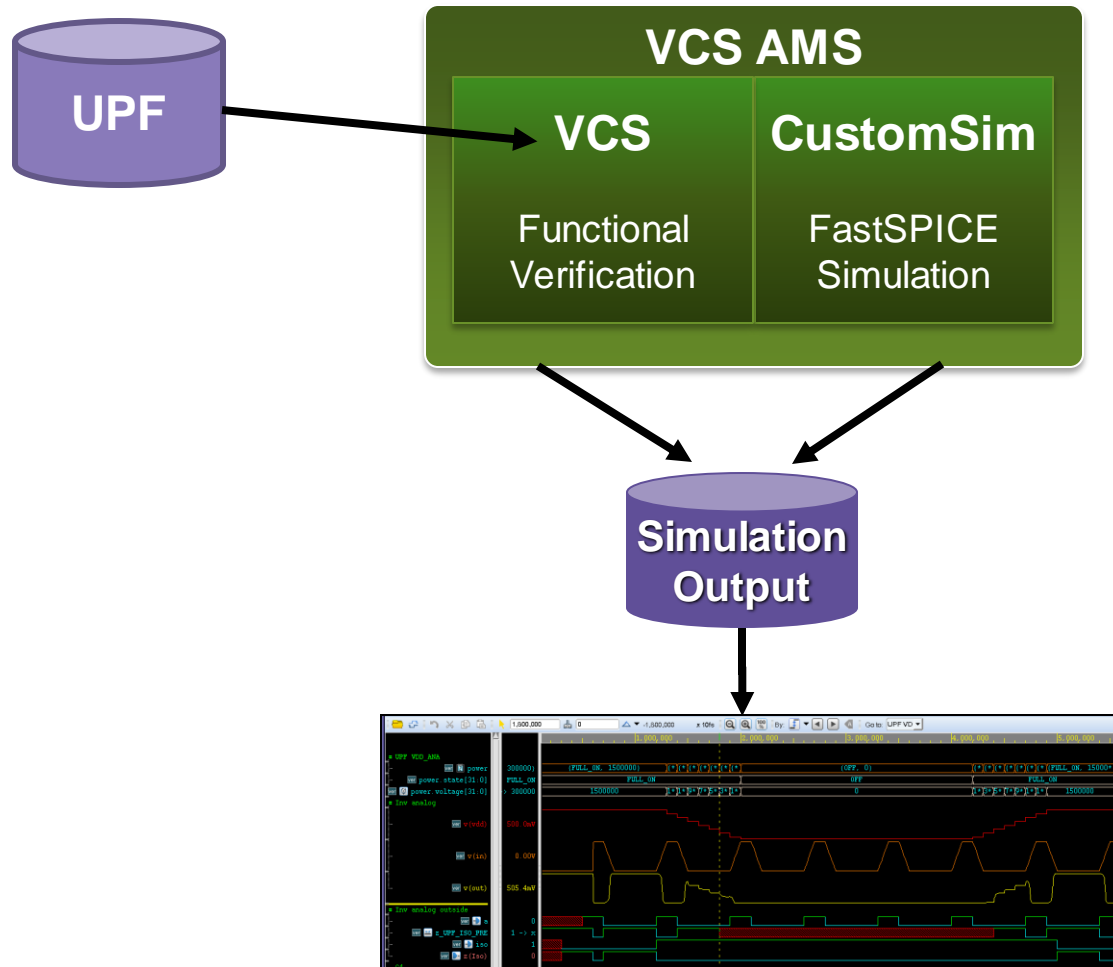
Self-checking

AMS testbench environment
AMS source generators
AMS functional coverage



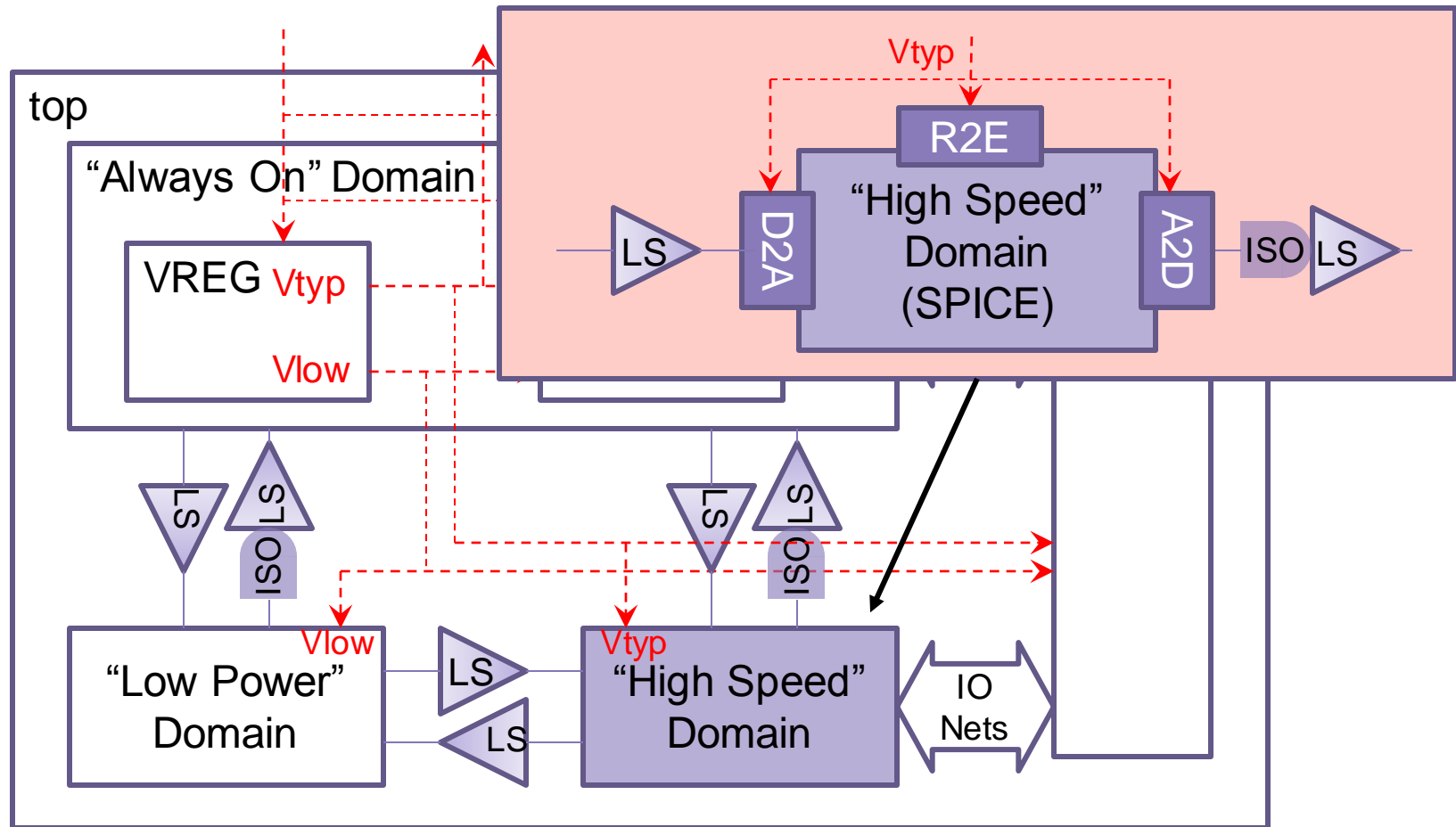
VCS AMS – Low Power Verification

VCS AMS with Native Low Power



VCS AMS – Low Power Verification

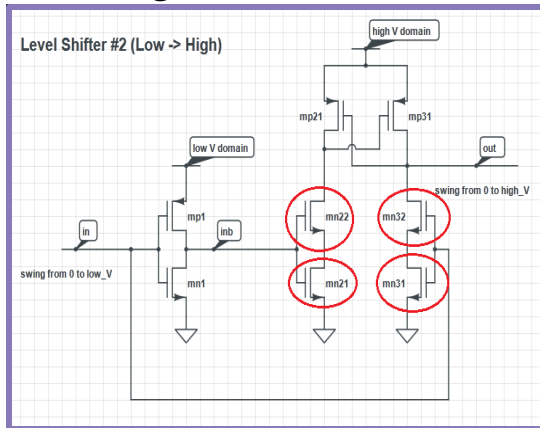
Introducing UPF-based Mixed-signal Verification



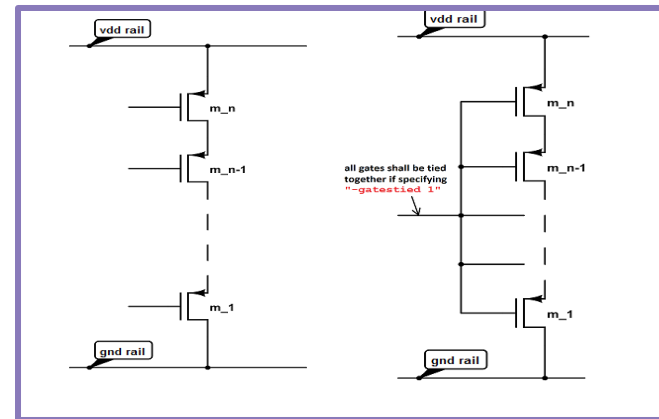
VCS AMS – Low Power Verification

Static Checking with Circuit Check (CCK)

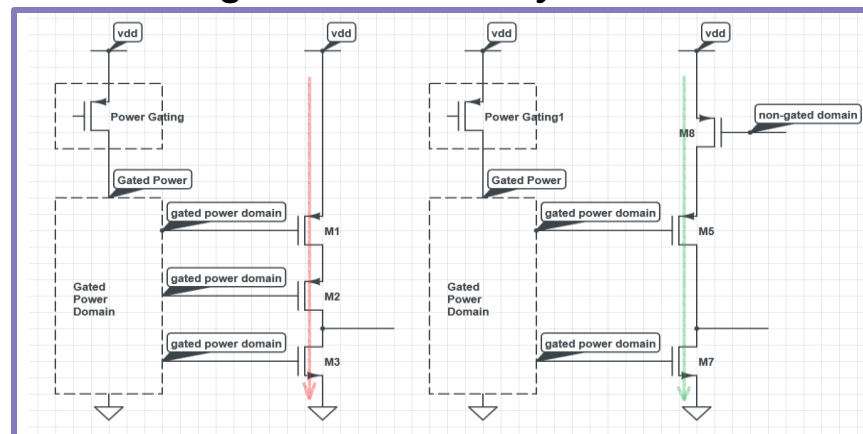
Missing Level Shifter Check



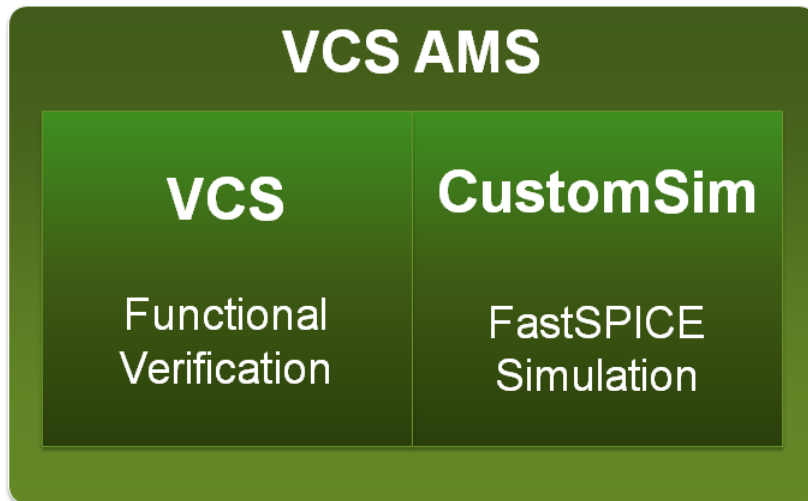
Stacking MOSFET between Rails



Leakage Path Induced by Gated Power



VCS AMS – Summary



- Performance
- Flexibility
- Broad Languages
- Debug

New!

→ **AMS Testbench**

New!

→ **Native Low Power**

AMS Testbench

Extending Digital Verification to Analog

Adiel Khan

Helene Thibieroz

Agenda

Overview

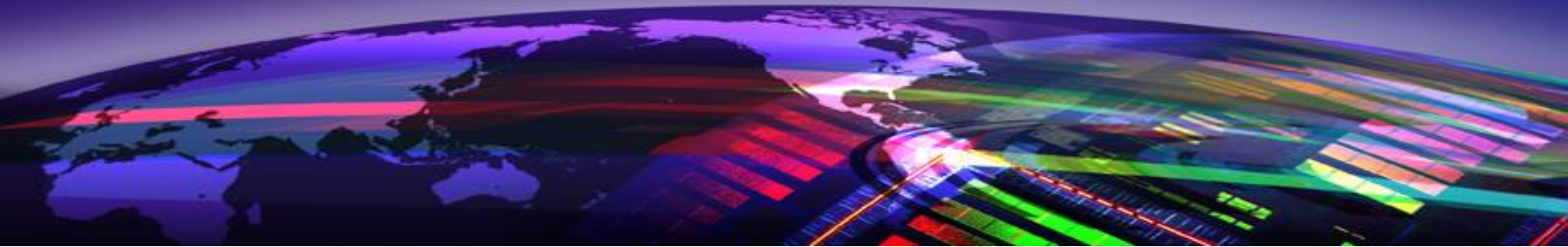
Technical features

Demo

Q&A

AMS Testbench

Overview



What is AMS Testbench?

- AMS Testbench refers to Synopsys proprietary analog extensions to the UVM standard
- Extension of UVM-based techniques for mixed-signal verification

Why AMS Testbench?

- Top-level verification required for mixed-signal SoCs
 - Increasing IP Integration
 - More complex interaction between analog and digital

AMS Testbench is Synopsys solution for mixed-signal coverage-driven verification methodology

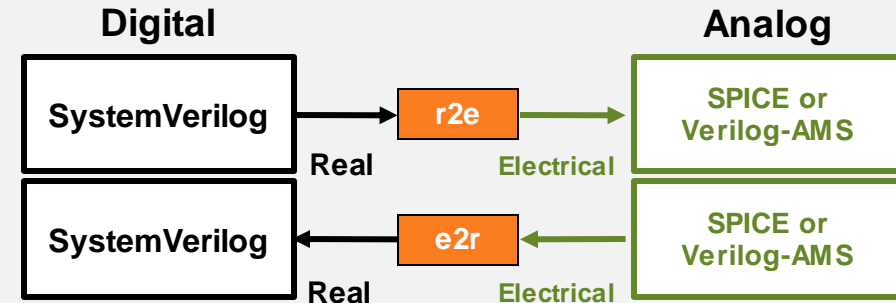
- Include analog during top-level verification and assume analog block characterization is enough
 - High risk of design re-spins
- Flow automation needed to include analog in full-chip verification planning strategy

VCS AMS for Regression

Digital Verification Techniques for Mixed-signal SoCs

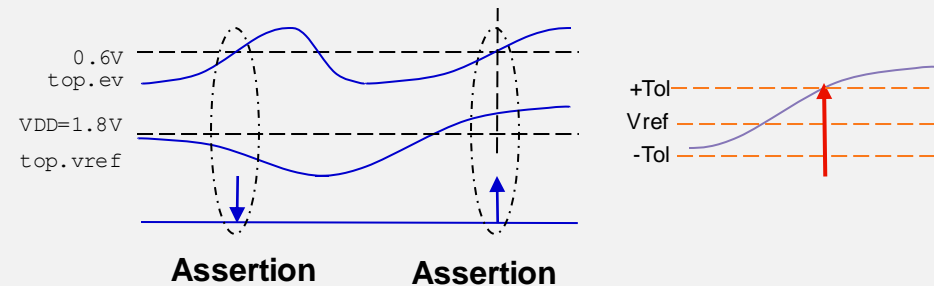
Connectivity

Electrical \Leftrightarrow Real conversion
Asynchronous analog events



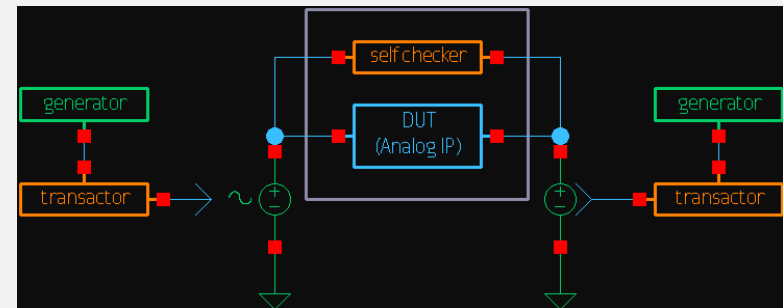
Metric-driven

AMS assertions
AMS constrained-random stimulus
AMS checkers
SystemVerilog real number modeling



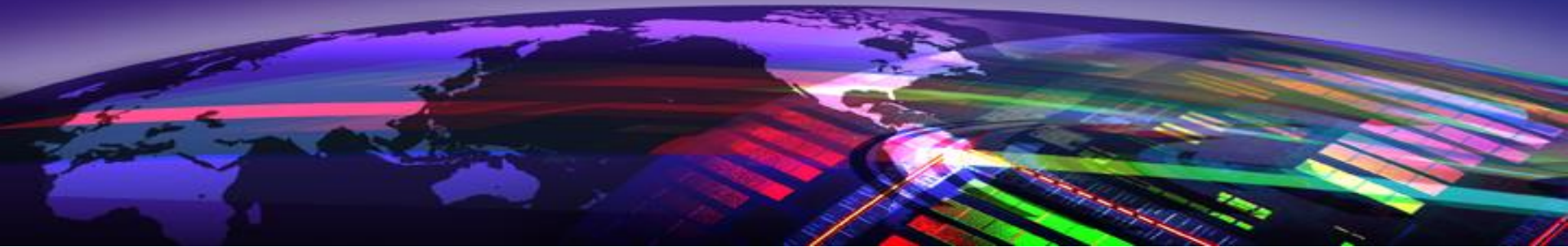
Self-checking

AMS Testbench environment
AMS source generators
AMS functional coverage

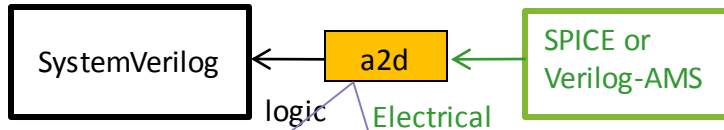


AMS Testbench

Digital Verification Techniques - Connectivity



Logic↔Analog Conversion

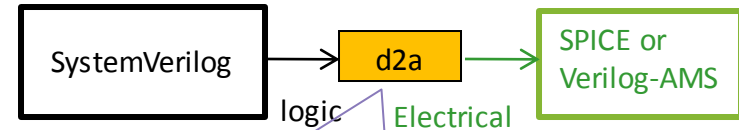


Automatic insertion of a2d connect models between SystemVerilog and SPICE

User can redefine the threshold

Example:

```
assign verilog_wire =  
    top.i1.i2.x1.clk;  
initial begin  
    verilog_reg =  
        top.i1.i2.x1.strb;  
    ...  
end
```



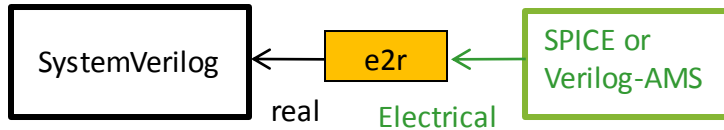
Automatic insertion of d2a connect models between SystemVerilog and SPICE

User can redefine the threshold

Example:

```
reg rst_reg;  
assign top.i1.i2.x1.rst = rst_reg;  
initial begin  
    ...  
    rst_reg = 1'b0;  
    #5 rst_reg = 1'b1;  
    ...  
end
```

Real↔Analog Conversion

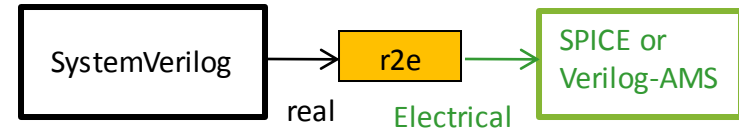


Easy XMR read access to internal analog signal voltage and current

```
$snps_get_volt(anode)
$snps_get_port_current(anode)
  anode: full hierarchical analog node name
```

Example:

```
real r;
always @(posedge clk)
  r <= $snps_get_volt(top.i1.ct1);
```



Easy XMR write access to internal analog signal voltage.

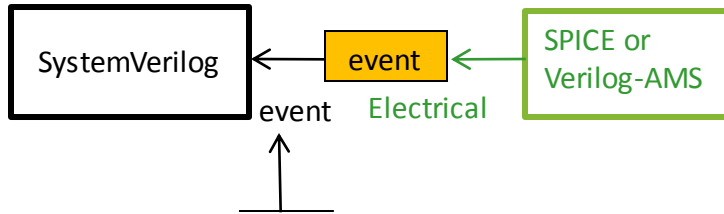
```
$snps_force_volt(anode, val|real)
$snps_release_volt(anode)
  anode: full hierarchical analog node name
  val|real: absolute value or real variable
```

Example:

```
real r;
initial
  $snps_force_volt(top.i1.ct1, 0.0);

always @(posedge clk) begin
  r <= r + 0.1;
  $snps_force_volt(top.i1.ct1, r);
```


Asynchronous Analog Events

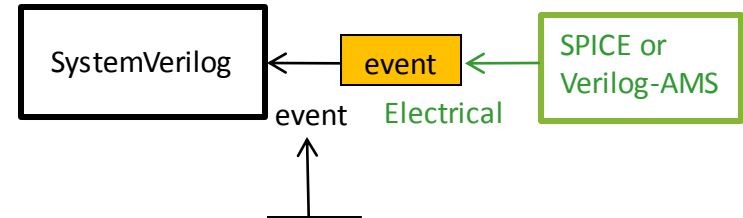


```
$snps_cross(aexpr[,dir[,time  
_tol [,expr_tol]]]);
```

aexpr: analog expression based on
system function

Example:

```
always  
  @(snps_cross($snps_get_volt(t  
    op.i1.ct1)-0.6,1))  
begin  
  $display("Signal ct1 is raising  
    above 0.6V");
```



```
$snps_above(aexpr[,time_tol  
[,expr_tol]]]);
```

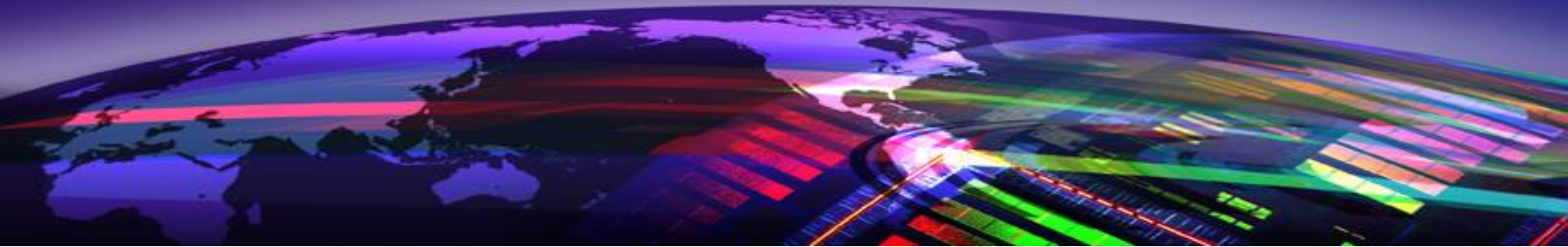
aexpr: analog expression based on
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Example:

```
always  
  @(snps_above($snps_get_volt(t  
    op.i1.ct1)-0.6))  
begin  
  $display("Signal ct1 is above  
    0.6V");
```

AMS Testbench

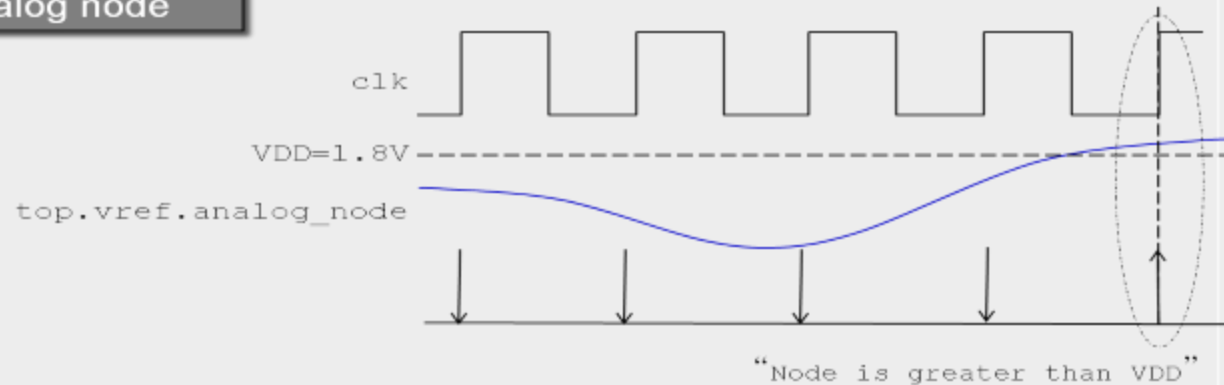
Digital Verification Techniques – Assertions and Checkers



Immediate Assertions

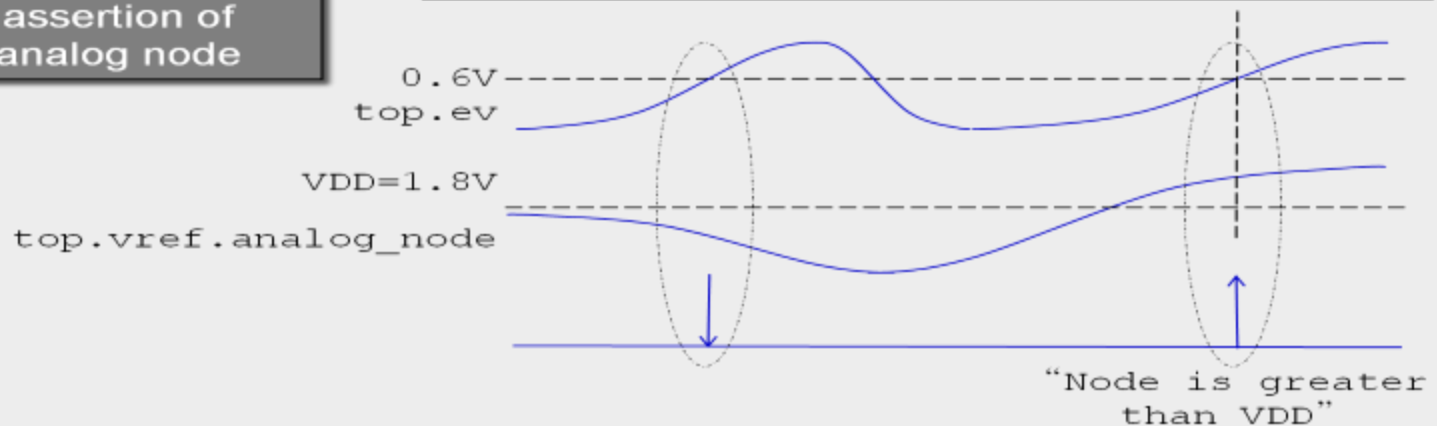
Synchronous
immediate
assertion of
analog node

```
always @(posedge clk)
  assert(top.vref.analog_node <= 1.8)
  else $error("Node is greater than VDD");
```

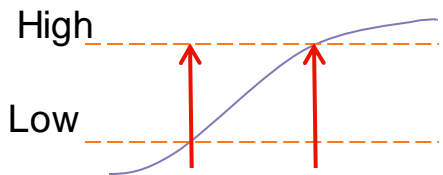
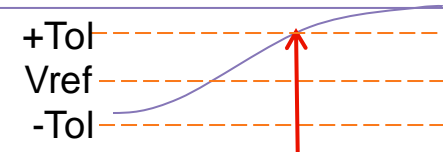
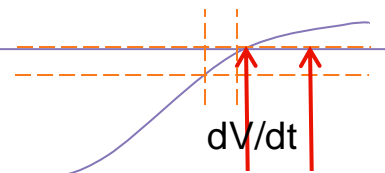
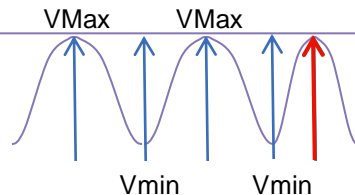


Asynchronous
immediate
assertion of
analog node

```
always @(snps_cross($snps_get_volt(top.ev)-0.6,1))
  assert(top.vref.analog_node <= 1.8)
  else $error("Node is greater than VDD");
```

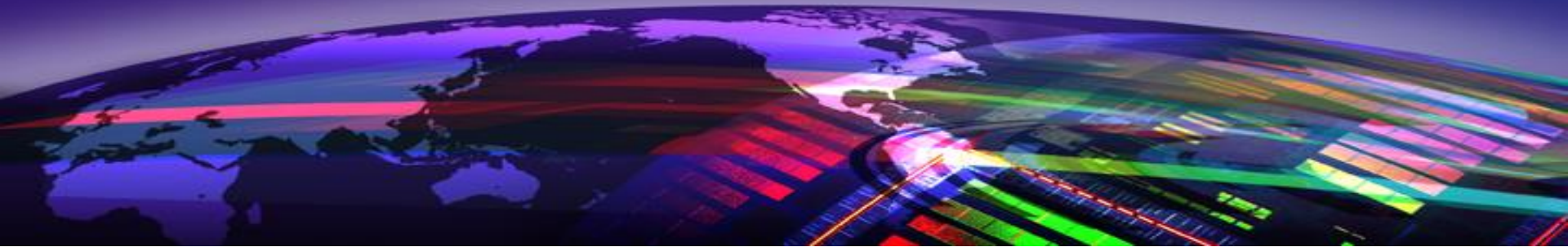


AMS Testbench Checkers

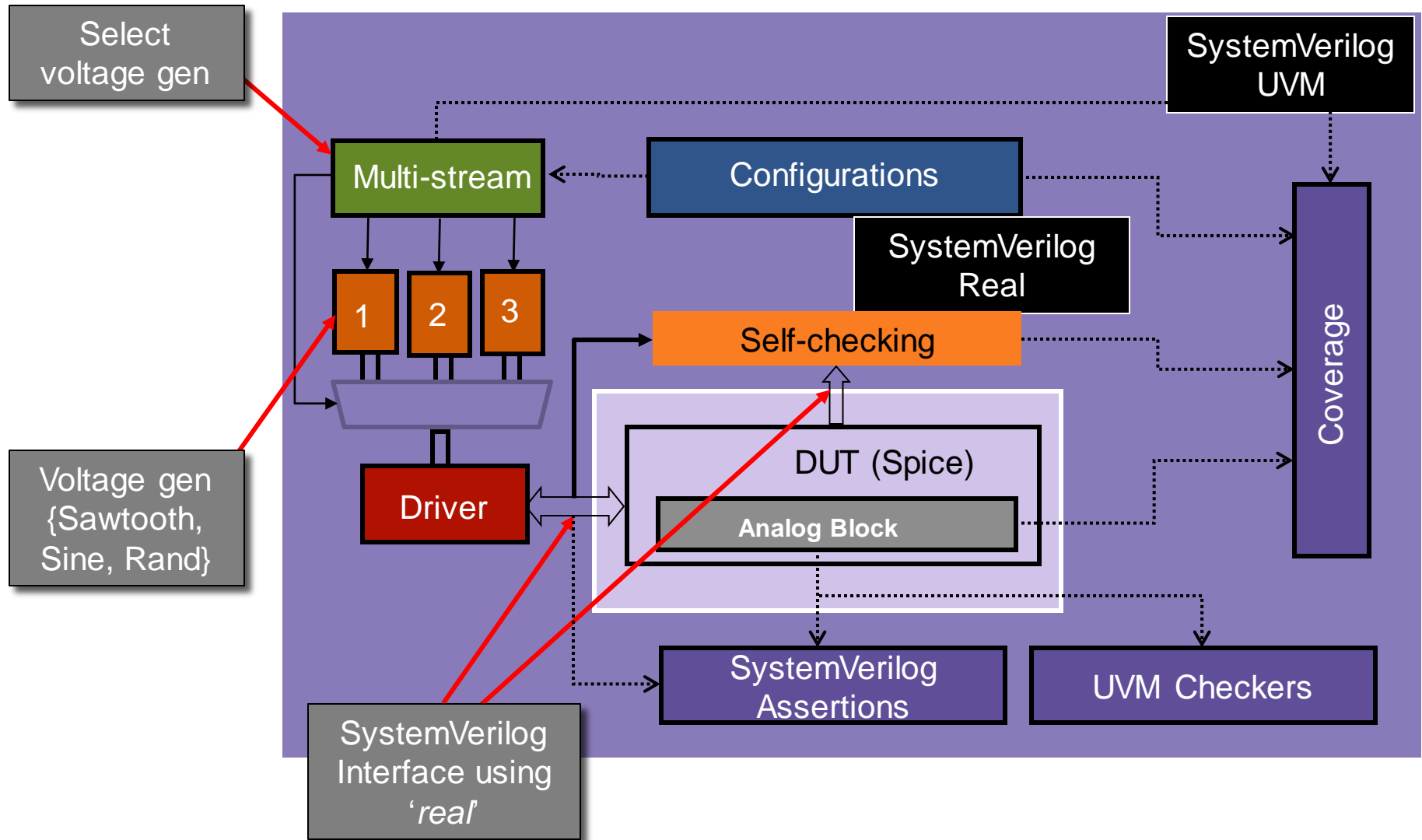
Checkers		
sv_ams_threshold_checker	Checks that analog signal remains within a given high and low threshold. Can perform this check synchronously or asynchronously	
sv_ams_stability_checker	Checks that analog signal remains below or above a given threshold. Can perform this check synchronously or asynchronously	
sv_ams_slew_checker	Checks that analog signal rises/falls with a given slew rate(+/- tolerance). Can perform this check synchronously or asynchronously	
sv_ams_frequency_checker	Checks that analog signal frequency is within a given tolerance	

AMS Testbench

Digital Verification Techniques – Self-checking

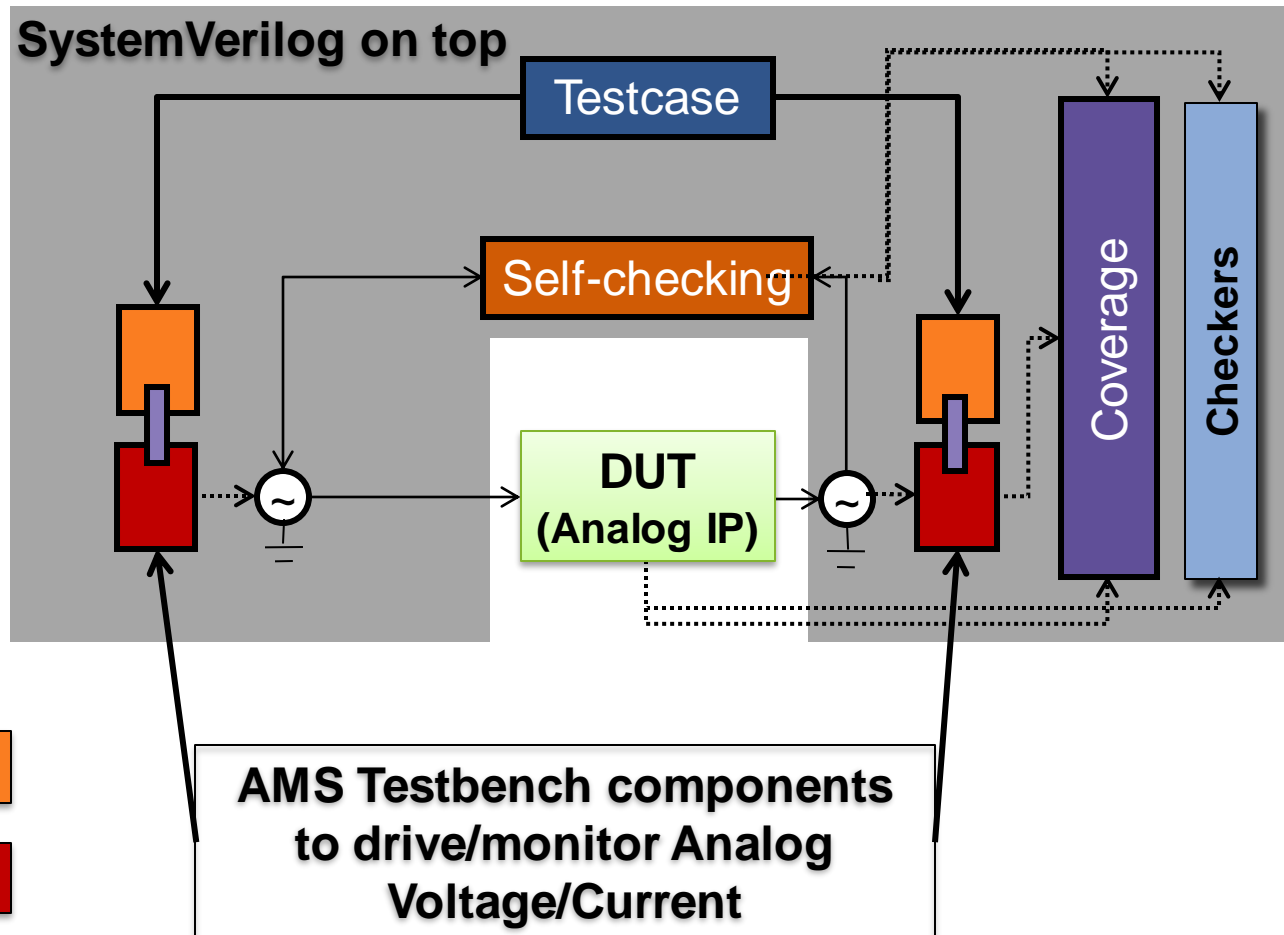


AMS Testbench Architecture

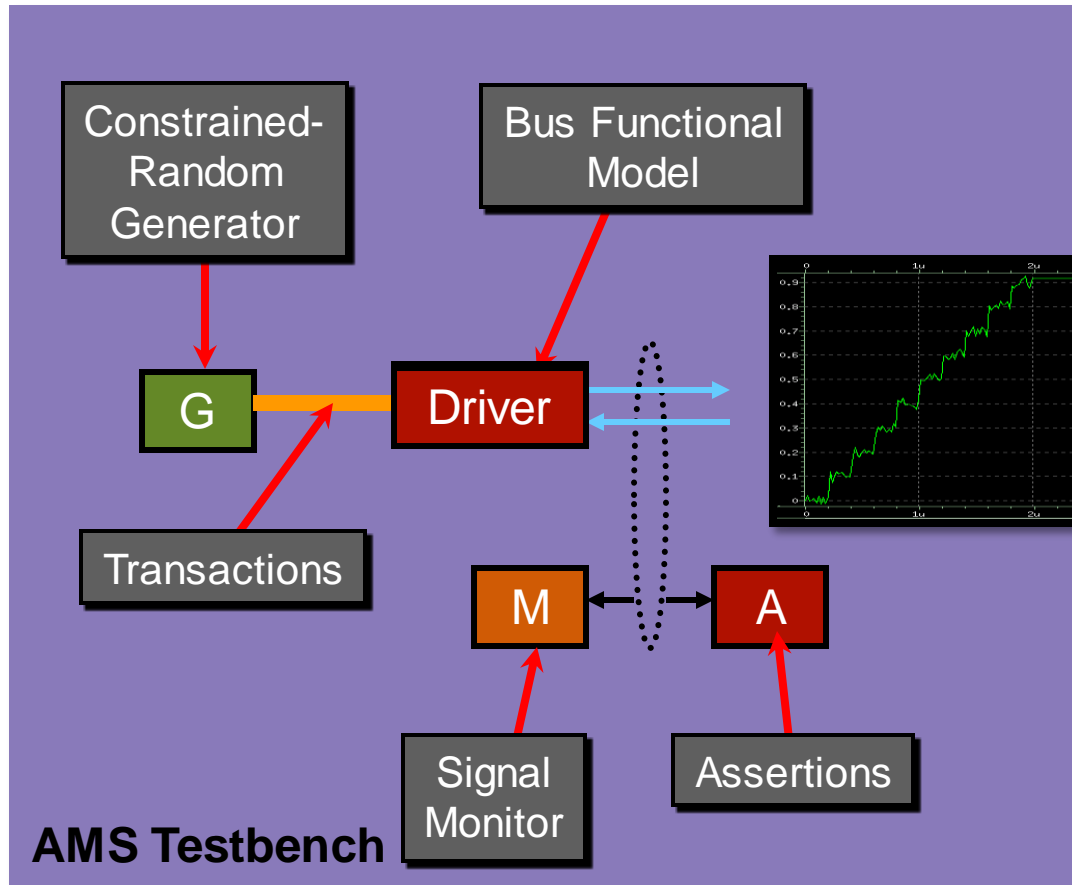


Analog IP Early Verification

Possible Usage Before SoC Integration



AMS Testbench Components



AMS Testbench Generators

- Sine voltage generator
- Sawtooth voltage generator
- Square voltage generator
- Fully customizable

AMS Testbench Checkers

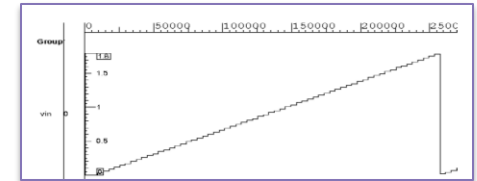
- Threshold
- Stability
- Window
- Slew Rate
- Frequency

AMS Testbench Generators

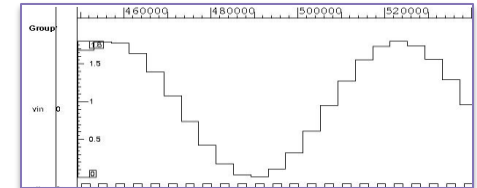
Checkers

`class sv_ams_generic_src` Provides base class infrastructure for building voltage generators

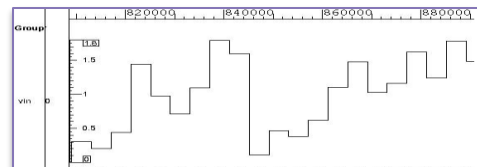
`sv_ams_sawtooth_voltage_gen` Base class aimed at generating sawtooth waveforms with minimum/maximum voltage and frequency



`sv_ams_sine_voltage_gen` Base class aimed at generating sine waveforms with minimum/maximum voltage and frequency



`sv_ams_rand_voltage_gen` Base class aimed at generating random waveforms with minimum/maximum random voltage sweep



AMS Testbench Generators

Sine voltage generator

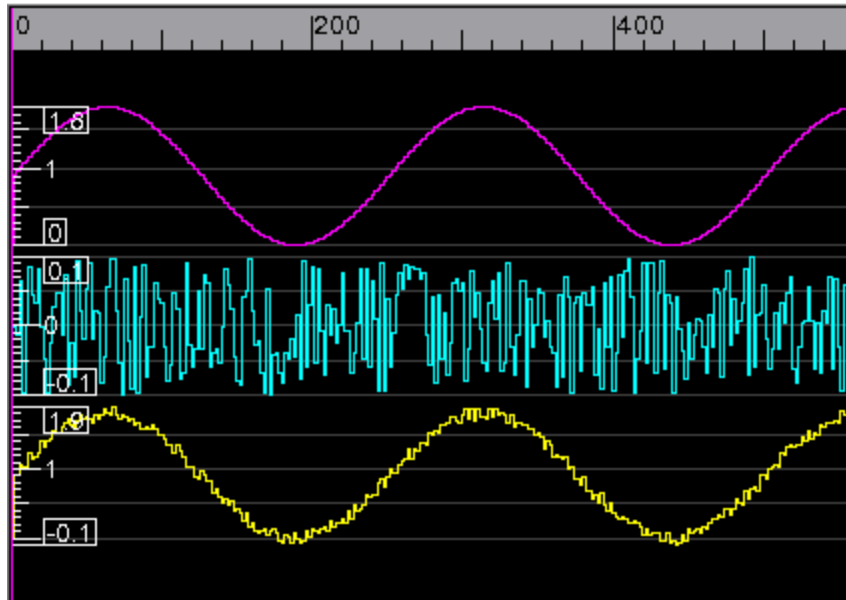
- Vmax=1.0V,
- Vmin=-1.0V
- F=1.0MHz

Construct sine wave generator
Default is auto-run throughout
run_phase()

```
...  
class my_env extends uvm_component;  
    ...  
    sv_ams_sine_voltage_gen#(-1.0, +1.0, 1.0E6) sGen_IN;  
  
    function void build_phase(uvm_phase phase);  
        super.build_phase(phase);  
        uvm_resource_db#(virtual ams_src_if)::  
            set("*", "uvm_ams_src_if", aif, this);  
        sGen_IN = sv_ams_sine_voltage_gen#  
            (-1.0, +1.0, 1.0E6)::type_id::create("sine", this);  
  
    endfunction
```

Example 1 - Noise Simulation

Noise Injection into Mixed-signal Simulation



Sine Wave
(0-1.8V)

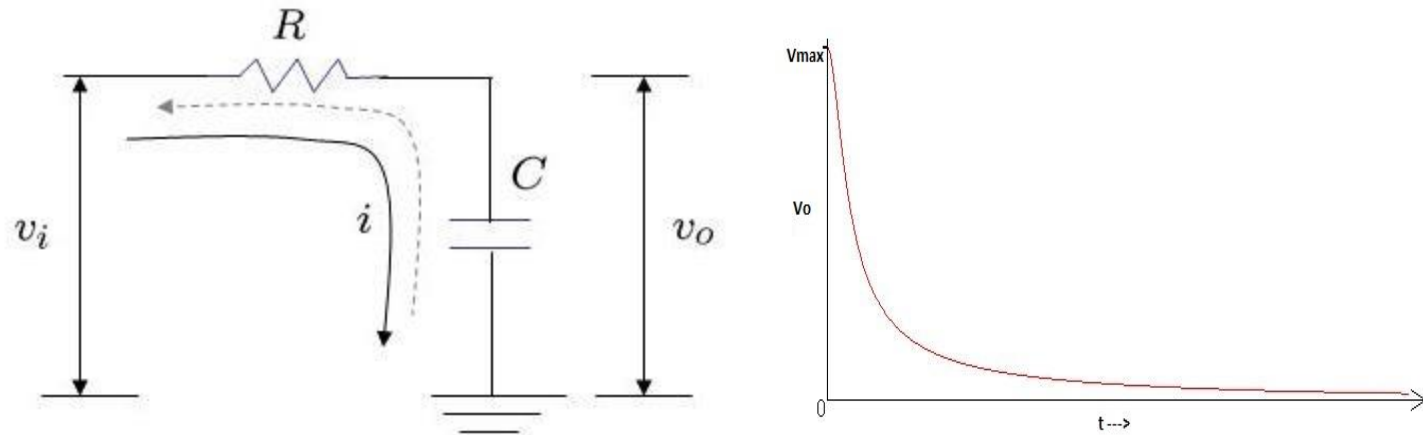
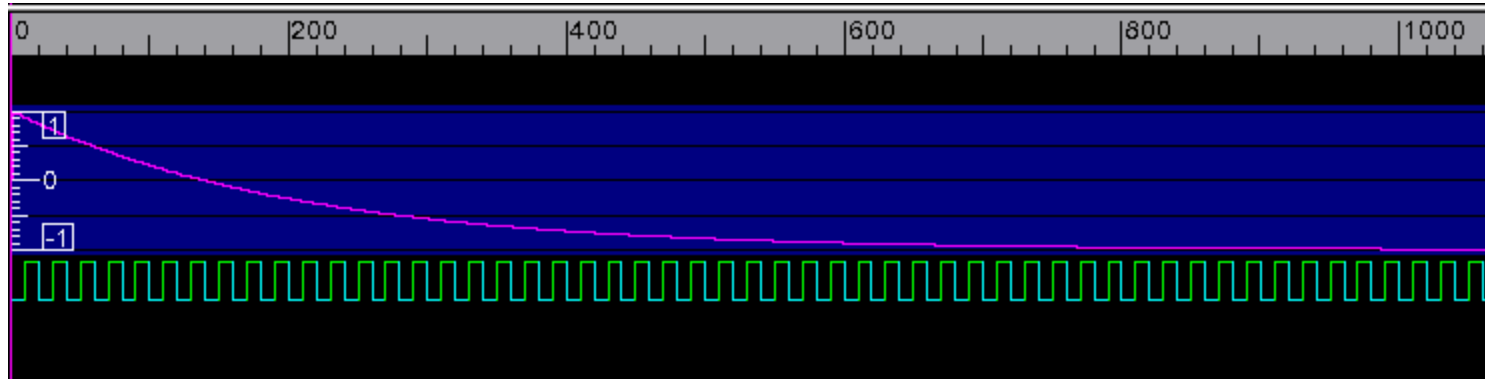
Noise
(-100 to 100mV)

Sine plus
noise

Random Noise Injected Using Sine Source

Example 2 - RC Voltage Generator

Can Be Used Within Testbench to Drive Analog Nodes

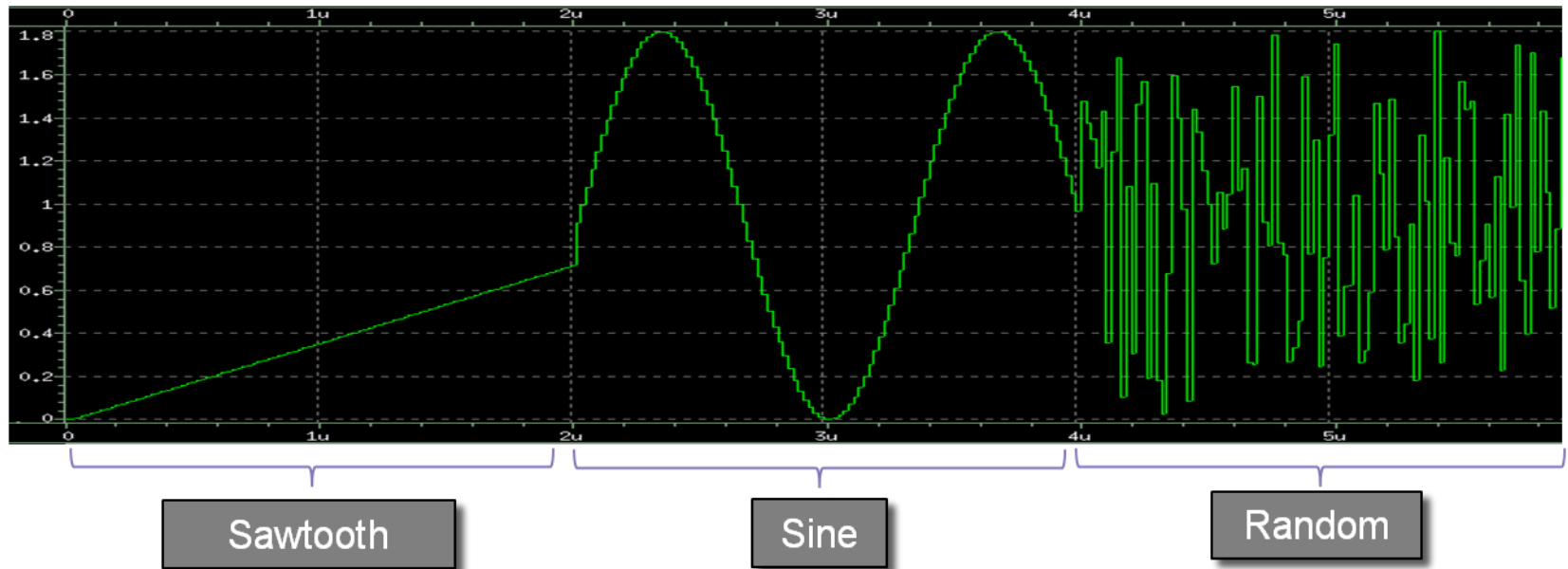


This custom source generator:

- $V_{min}=-1V$, $V_{Max}=1V$, $Freq=1MHz$, $RC=200ns$

Example 3: Custom Voltage Generator

Different Source Types Can Be Combined



AMS Functional Coverage

Analog and Digital Coverage in Same Verification Plan

The screenshot shows the VeriSign coverage tool interface. The main table lists coverage items with their scores, goals, and weights. The 'cp_vmax' item is highlighted, and a detailed view of its status is shown below.

Cover Group Item	Score	T	U	Goal	Weight	AtLeast	PerInst	Overlap
tb::ana_cov:cg_vin	52.78%	67	36	100%	1	1	0	1
cp_vi	93.75%	16	1	100%	1	1		1
cp_vmax	33.33%	3	2	100%	1	1		1
cc	31.25%	48	33	100%	1	1		

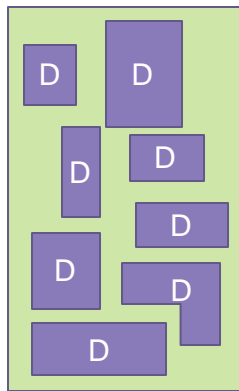
Status	cp_vmax	cp_vi	Type	At Least	Size	Hit Count
✓	VNOM	R_0_1	Auto	1	1	6
✓	VNOM	R_1_2	Auto	1	1	7
✓	VNOM	R_2_3	Auto	1	1	3

By clearly referencing both analog and digital coverage groups, both domains can be verified together

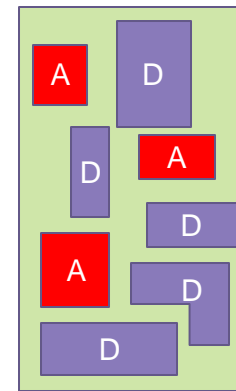
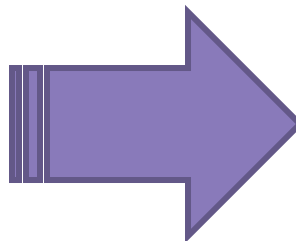
AMS Testbench - Summary

Functional verification methodology for mixed-signal SoC

- Extends SystemVerilog Testbench Environment to mixed-signal domain
- Provide mixed-signal coverage in SystemVerilog testbench



UVM



AMS Testbench



VCS AMS in STMicroelectronics

Pierluigi Daglio

AMS Design Verification Flows Manager

SPA - TR&D Smart Power
Design Enablement

Mauro Scandiuzzo

Field Application Engineer

AMS & IPG Marketing & Applications



DVCon Europe - Munich
14th October 2014

- STMicroelectronics Product Segments
- STMicroelectronics Analog/Mixed-Signal Scenario
 - Verification flow and purpose
 - The application
 - Design and process
- Usage of Unique VCS AMS Features for Superior Productivity
 - Assertions
 - Save and Restore
- Conclusions

Product Segments

42



Sense & Power and Automotive Products (SP&A)

Analog, MEMS
& Sensors
(AMS)



Automotive
Product Group
(APG)



Industrial &
Power Discrete
Group
(IPD)



Embedded Processing Solutions (EPS)

Digital
Convergence
Group
(DCG)



Imaging,
BiCMOS, ASIC
& Silicon
Photonics
(IBP)



Microcontroller,
Memory &
Secure MCU
(MMS)



Smart Power Product Segments

43



Sense & Power and Automotive Products (SP&A)

Analog, MEMS
& Sensors
(AMS)

Automotive
Product Group
(APG)

Industrial &
Power Discrete
Group
(IPD)

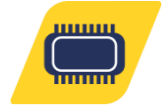


Embedded Processing Solutions (EPS)

Digital
Convergence
Group
(DCG)

Imaging,
BiCMOS, ASIC
& Silicon
Photonics
(IBP)

Microcontroller,
Memory &
Secure MCU
(MMS)



















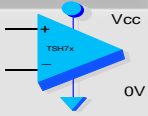
- Audio amplifier
- Ultrasound echography
- High performance analog
- Airbag
- Gasoline Direct Injection
- ESP/ABS
- Car Radio
- Precision battery monitoring

- HDD Power Combo
- Printer head & motor drivers
- Motherboard DCDC converter
- LED bulb driver
- Power Line driver
- Mobile power management
- Mobile display drivers

Smart Power Application Fields

by Technology Platform Segment

5

BCD Segment	Technology Platforms	Application Field
Off Line BCD 600V – 5kV	<ul style="list-style-type: none"> BCD6s OFFLINE BCD6s HV Transformer 0.32μm 	 Lighting  Motors  Electrical Car
SOI BCD 190V – 300V	<ul style="list-style-type: none"> SOI-BCD6s 0.32μm SOI-BCD8s 0.16μm 	 Full digital amplifier  Ultrasound Ecography  AMOLED Power Supply
Advanced BCD 7V – 100V	<ul style="list-style-type: none"> BCD8A/As 0.18μm BCD8sP 0.16μm BCD8sAUTO 0.16μm BCD9s 0.11μm BCD9sL 0.11μm BCD10 90nm BCD11 65nm 	 HDD  GDI  Audio amplifier  Power Line modem  Printers  Airbag Body  ABS ESP  Power Supply Power Management
High Voltage CMOS 16V – 40V	<ul style="list-style-type: none"> HVG8A 0.18μm HVCMOS8A 0.18μm 	 Electronic labels  E-book  Automotive Sensor IC  Bio Medical  Advanced Analog

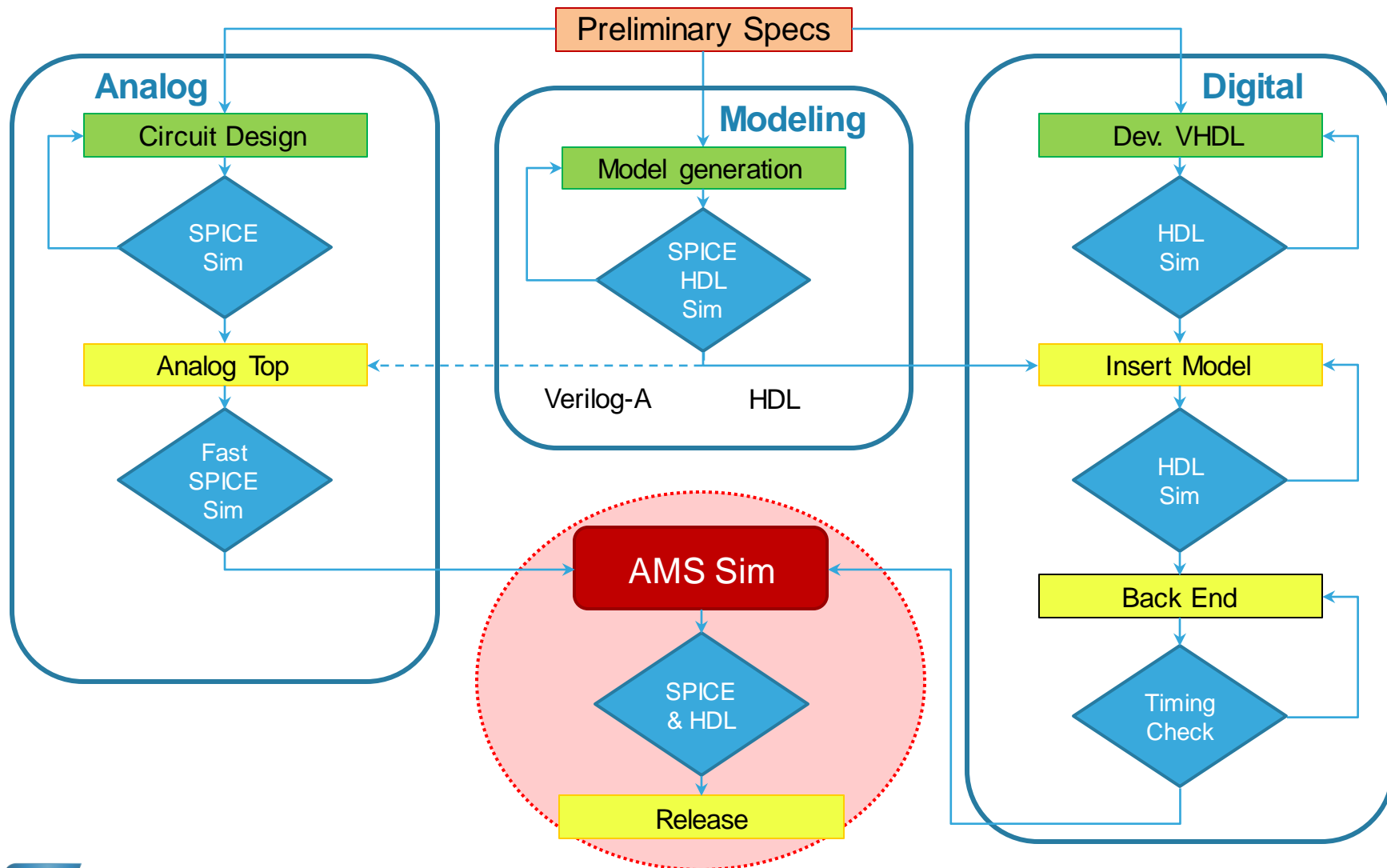
ST Analog/Mixed-Signal Scenario

45

- Simulation and verification of large IPs and macro-cells
 - Transistor-level simulation
 - Static and dynamic electrical rule checks (ERC)
 - Safe operating area (SOA)
 - Analog behavioral languages (Verilog-A)
- Simulation and verification of A/M-S systems
 - System-level analog/digital co-simulation
 - Digital test benches
 - Fast and reliable simulation (speed & accuracy)
 - HDL languages and analog behavioral languages

AMS Verification Flow

7



AMS Verification Purpose

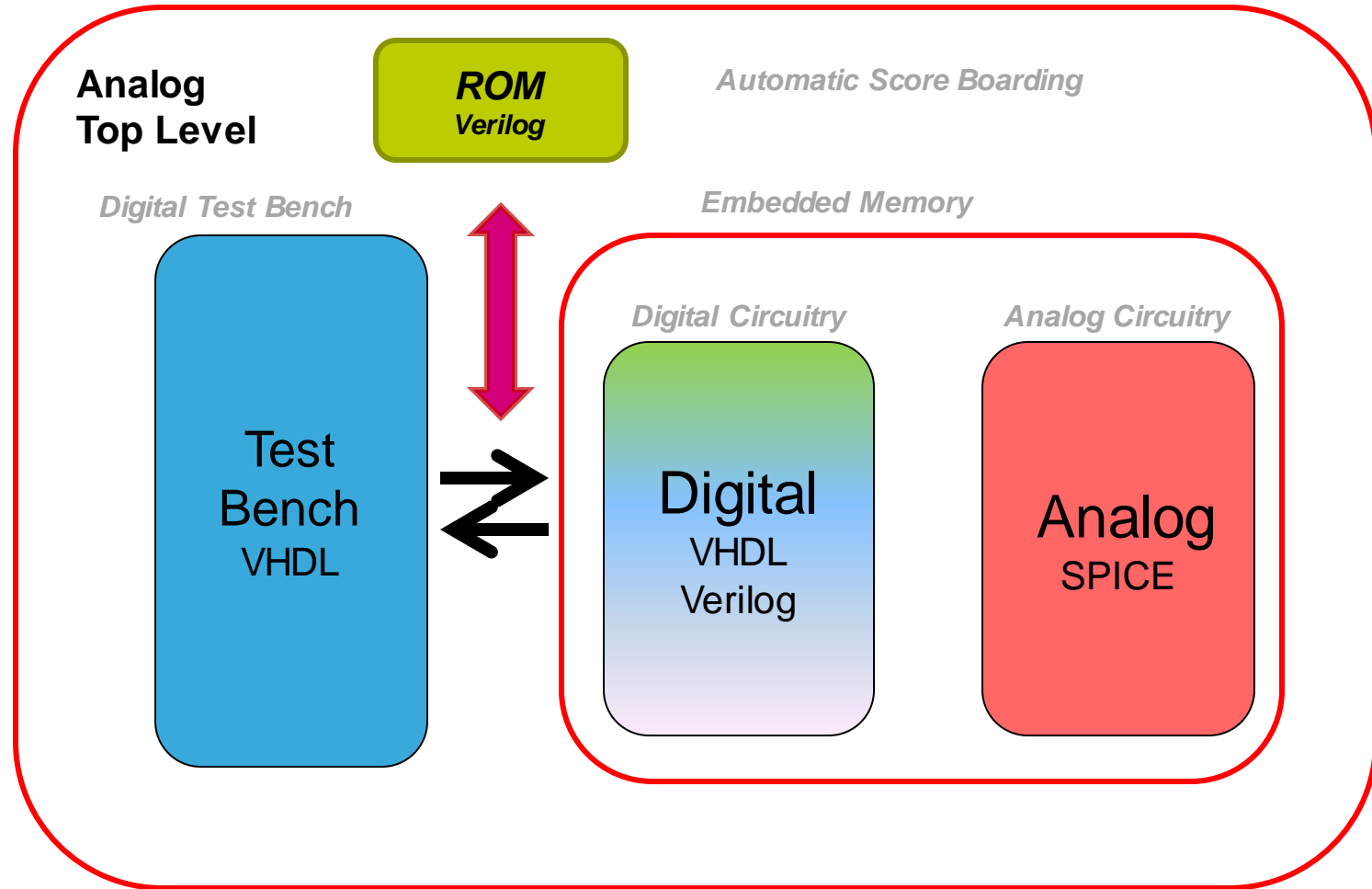
8

Purpose: Verify complex designs at top-level both with digital and analog parts

- It is possible to verify complex designs mixing among ...
 - **netlist configurations**
 - digital: VHDL or Verilog post synthesis
 - analog: pre-layout or post-layout (trade-off simulation time)
 - **operation conditions**
 - digital: for Verilog (min & max delay)
 - analog: TYP, SSA, FFA,
 - **modes**
 - Usermode: boot, read, erase, prog with algorithm, ...
(user set of operations)
 - Testmode: DMA MTX_CELL, DMA REF_CELL, Erase Reference matrix
(IP validation)

AMS Verification - The Application

48



AMS Verification Design and Process

49

Design Complexity

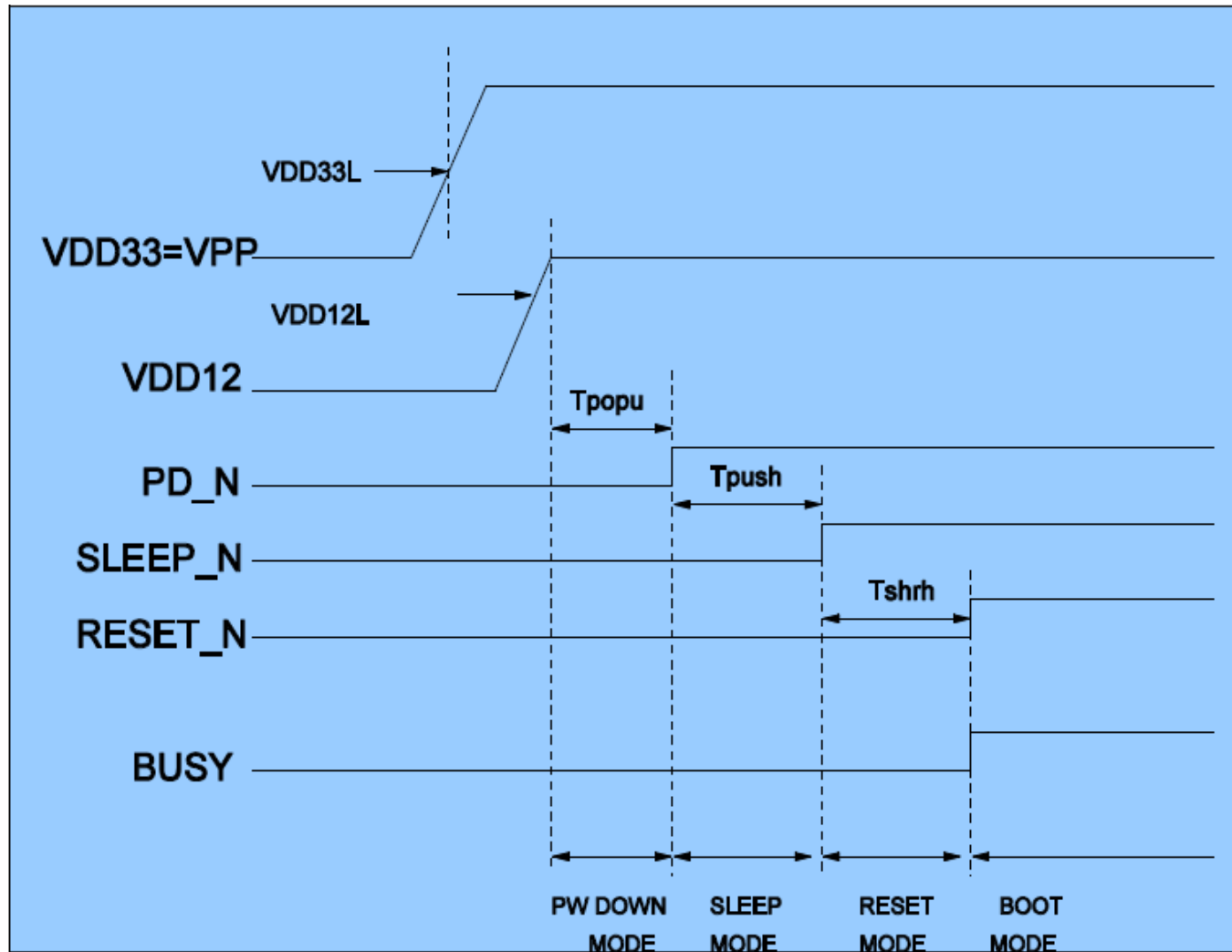
- Memory Size 136KB Single Module
 - Organized into 3*32KB-sector, 5*8KB and 1*TF sector (8KB)
- Double Voltage Supply
 - Analog supply: 1.62V-3.6V
 - Digital supply: 1.08V-1.32V
- x32-bit Reading (internally, 32b + 1b Redundancy) and Writing (internally, 2 bits by 2)
- Embedded Program/Erase Code

Technology

- Low Power: Double Poly, Triple-Well
- Differential Oxide: GO1-LV, GO2-MV, HV
- Low Power Consumption
- MIM Capacitors
- High Resistivity Poly1 Resistors Available

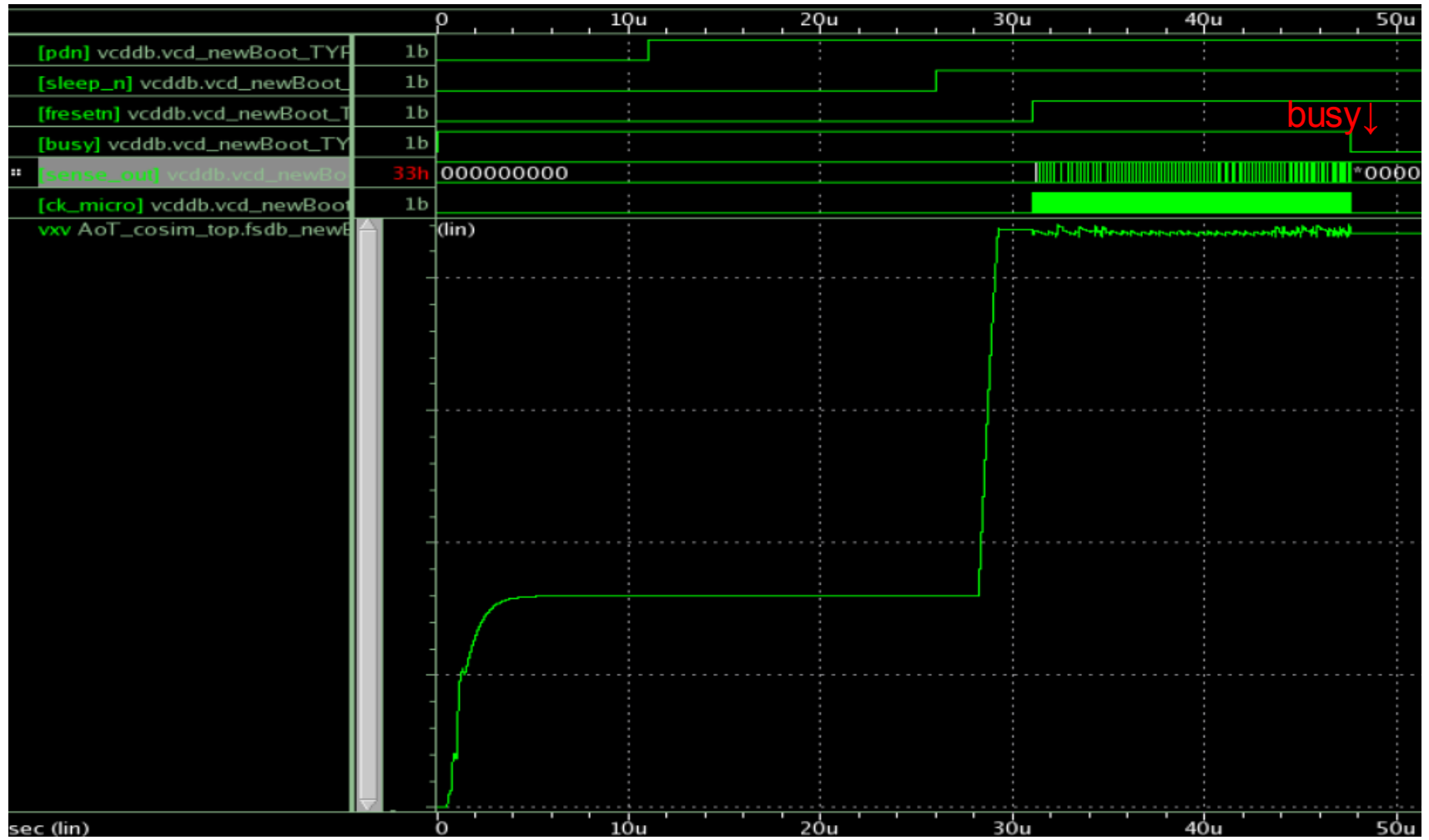
Power-up Sequence

11



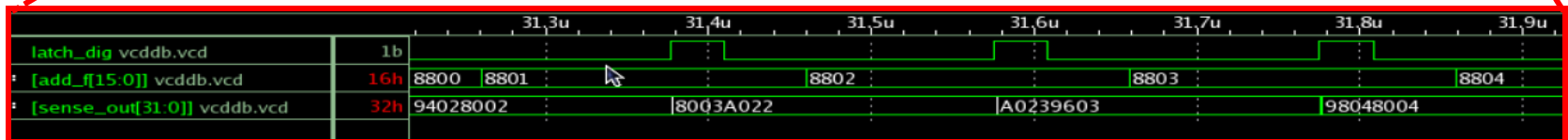
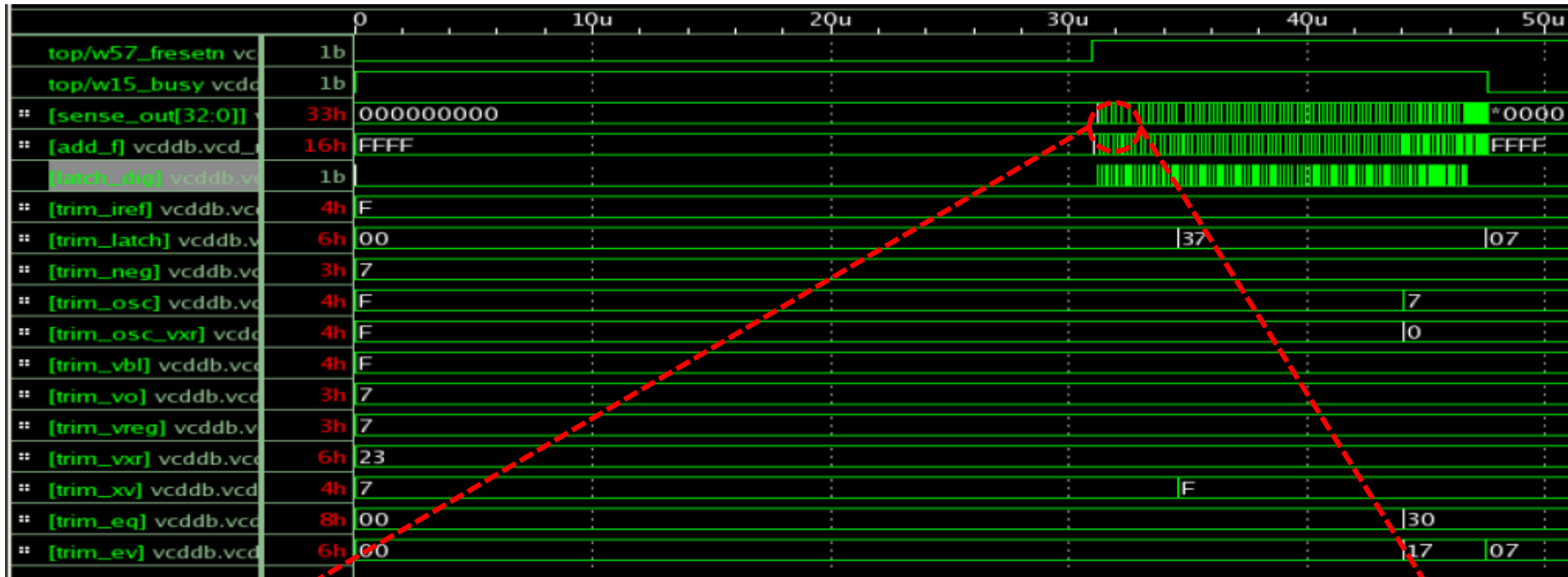
Waveforms - Boot Operations

12



Boot Trimming - Sense Out Details

13



VCS AMS Automatic Checks w/Assertions

14

Digital input

Analog output

Trigger

```
checker UCK (.addr(add_f[15:0]), .data(sense_out[31:0]), .clk(latch_dig));  
  
module checker (  
  addr ,  
  data ,  
  clk  
);
```

Checker

```
assign scoreboard = ce ? mem[addr] : 32'b0;  
  
initial begin  
  file= $fopen(report.dat);  
  $readmemb("mem.dat", mem);  
end
```

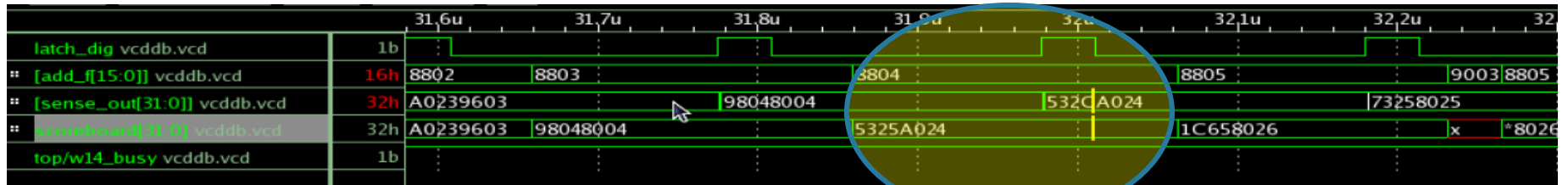
Scoreboard

```
property BUS_MATCH (clk, busA, busB , enable);  
  @(negedge clk)  
  enable | => (busA == busB );  
endproperty  
  
myCheck : assert property (BUS_MATCH (clk, data, scoreboard, ce))  
begin  
  $fdisplay(file, "@time %t - OK ++ data %h ", $time, data);  
end  
else begin  
  $fdisplay(file, "@time %t -FAIL ++ data %h", $time, data);  
  $warning("@time %t -FAIL ++ data %h", $time, data);  
end
```

Assertion

Assertions Simulation Results

15



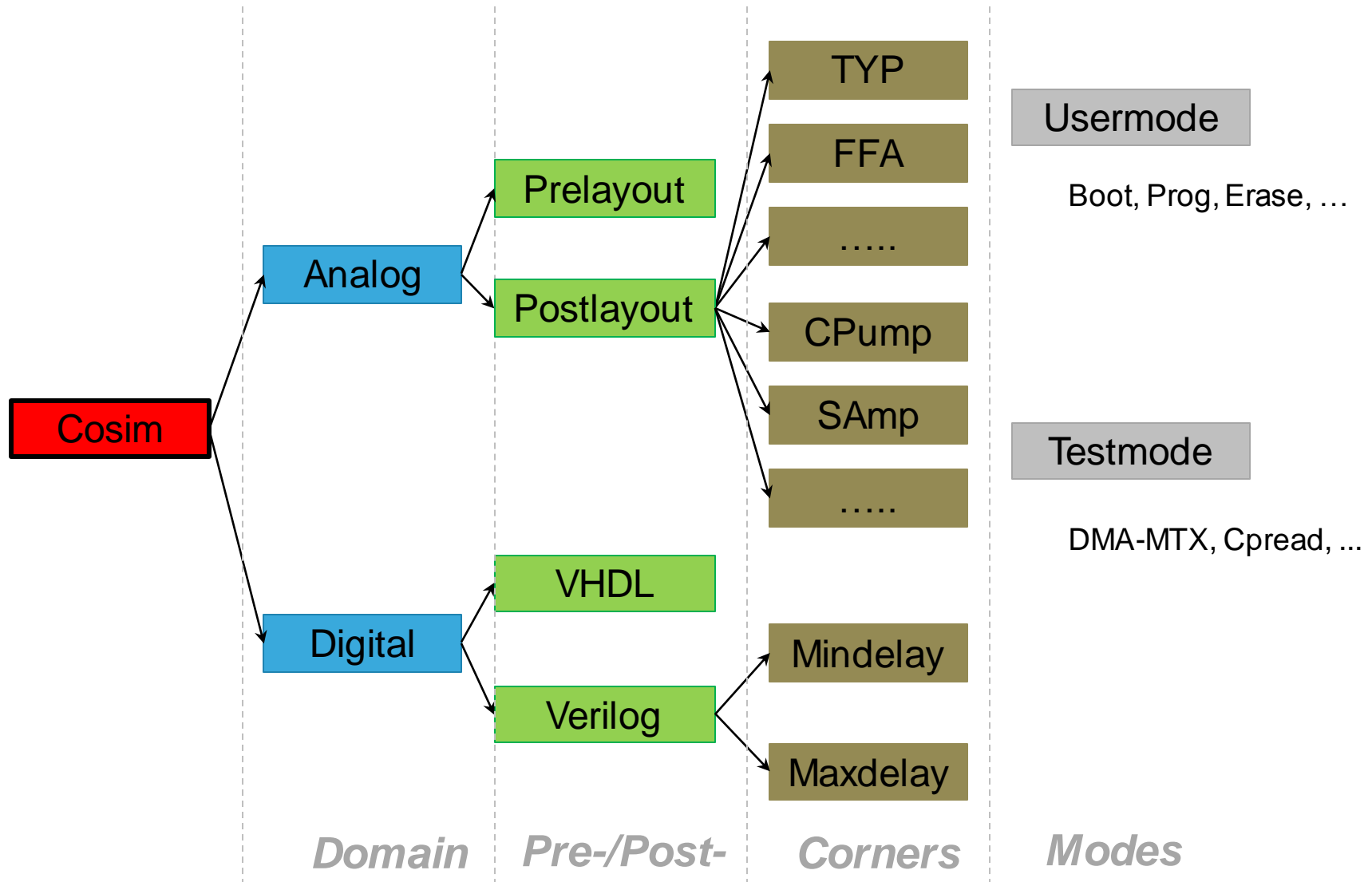
report.dat

```
File Edit Search Preferences Shell Macro Windows
/prj/nvem/mauro/H9A/opus_ams_6.1@time 31400.00 ns - OK ++ data 8003a022
@time 31609.00 ns - OK ++ data a0239603
@time 31808.00 ns - OK ++ data 98048004
@time 32011.00 ns -FAIL ++ data 532ca024
@time 32214.00 ns -FAIL ++ data 73258025
@time 32417.00 ns -FAIL ++ data 73258025
@time 32586.00 ns -FAIL ++ data e028066c
@time 32788.00 ns -FAIL ++ data e028066c
@time 32959.00 ns -FAIL ++ data 90058305
@time 33162.00 ns -FAIL ++ data b195a235
@time 33366.00 ns -FAIL ++ data 8f057135
@time 33603.00 ns -FAIL ++ data a02593f5
@time 33807.00 ns -FAIL ++ data 96078147
@time 34010.00 ns -FAIL ++ data 8018a027
@time 34213.00 ns -FAIL ++ data 70765056
@time 34416.00 ns - OK ++ data ffffffff
@time 34587.00 ns -FAIL ++ data 0e450036
@time 34789.00 ns -FAIL ++ data 0e450036
```

Report

VCS AMS Save and Restore - Setup

55



VCS AMS Save and Restore Capability

56

- A "memory image" of the simulation can be saved and restored at a later time
- At restore time, the netlist and the simulation set-up cannot be changed
- Typically used for running many functional simulations on the same design after the power-up

Save

```
% simv -ucli  
ucli% run 100  
ucli% save sim_state  
ucli% quit
```

Restore

```
% simv -ucli  
ucli% restore sim_state  
ucli% run
```


VCS AMS Save and Restore Performance

57

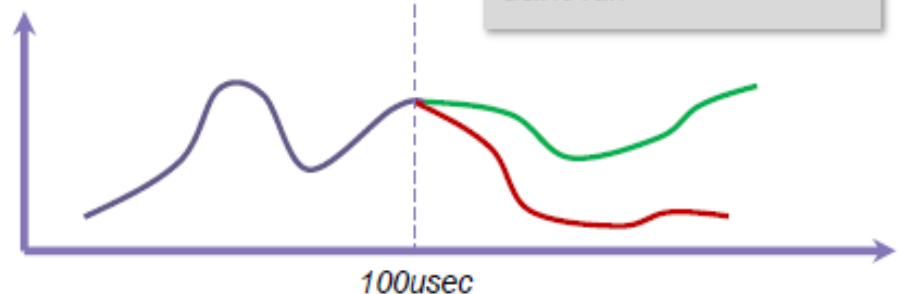
- Multiple runs can be executed by forcing a test selector variable
 - A run is chosen by forcing the test selector via UCLI

```
module testbench;  
int tst;  
...  
case (tst)  
  1: test1( ); // Run Test No 1  
  2: test2( ); // Run Test No 2  
  3: test3( ); // Run Test No 3  
  4: test4( ); // Run Test No 4  
  5: test5( ); // Run Test No 5  
default: test0 ( );  
endcase  
...  
end
```

```
% simv -ucli  
ucli% run 100  
ucli% save sim_state  
ucli% quit
```

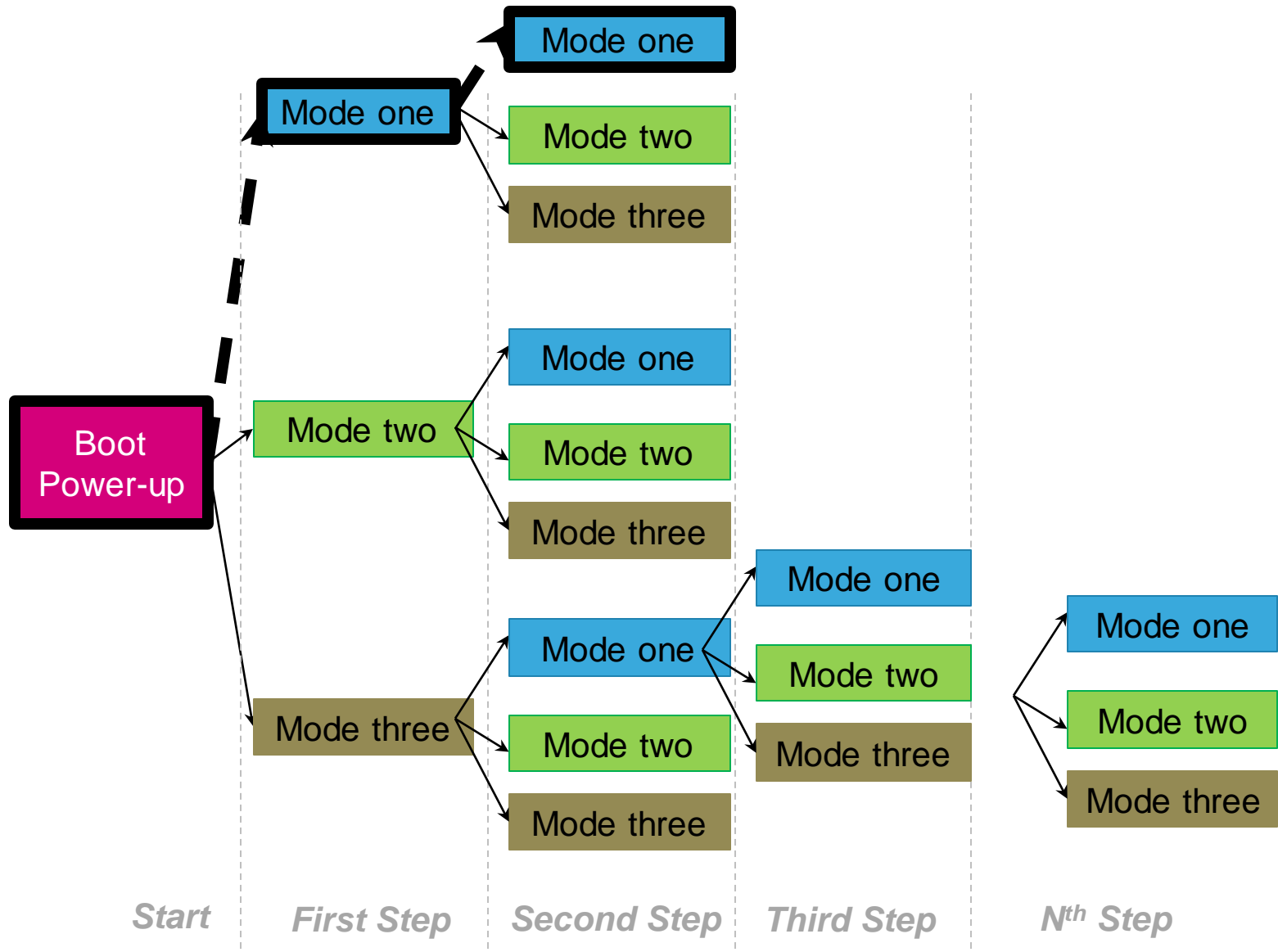
```
% simv -ucli  
ucli% restore sim_state  
ucli% force testbench.tst 1  
ucli% run
```

```
% simv -ucli  
ucli% restore sim_state  
ucli% force testbench.tst 4  
ucli% run
```



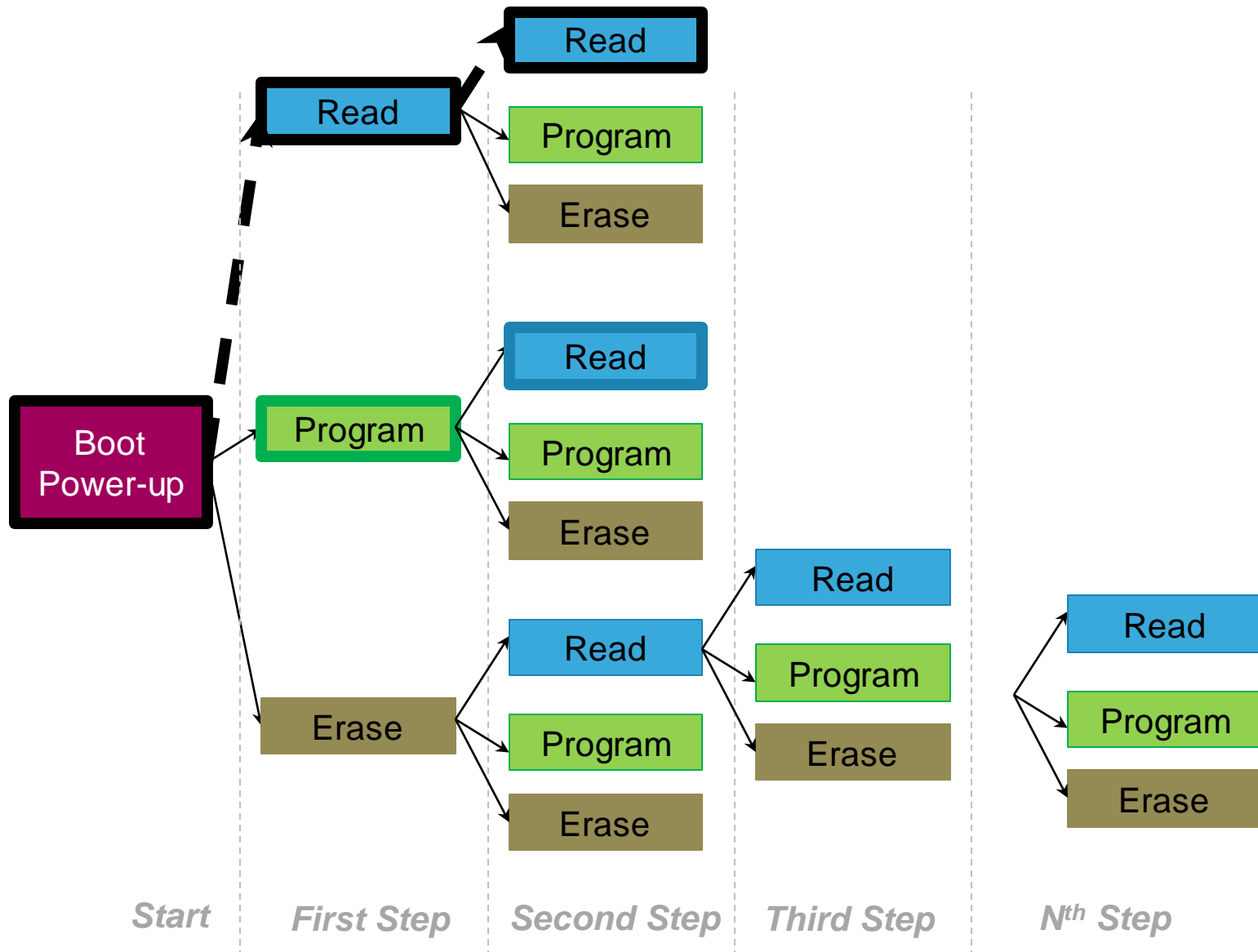
Multi-Mode Approach w/Save and Restore

58



Real Application Save & Restore Capability

59



Save and Restore - Boot & Multiple Read

60

Testbench

```
-----
REPORT "*** INFO: Boot User Mode";
-----
fresetn <= '1';
WAIT FOR 1*UsrPeriod;
IF busy='1' THEN
  WAIT UNTIL busy='0';
  REPORT "*** INFO: Boot Completed";
ELSE
  REPORT "*** ERROR: Busy has not started" SEVERITY ERROR;
END IF;
uRead(X"9003", i_data); -- read status
ASSERT (i_data = c_B6) REPORT "*** ERROR: Flash is not ready for read (SR: 0x" & hex_image(i_data) & ")" SEVERITY ERROR;

-- case for MultiTest validation

WAIT FOR 10 us;

case SEL is
  when "01" => fREAD(X"0000",i_data);
  when "10" => fREAD(X"1FFF",i_data);
  --when "11" => fREAD(X"0000",i_data);
  when others => fREAD(X"1111",i_data);
end case;

WAIT FOR 10 us;

case SEL is
  when "01" => fREAD(X"0000",i_data);
  when "10" => fREAD(X"1FFF",i_data);
  --when "11" => fREAD(X"0000",i_data);
  when others => fREAD(X"1111",i_data);
end case;

fRead(X"0000", i_data); -- just to trigger a read from Flash and change
fRead(X"0004", i_data); -- read from Flash
fRead(X"0000", i_data); -- just to trigger a read from Flash and change
fRead(X"0004", i_data); -- read from Flash

WAIT FOR 5000*UsrPeriod; -- Off Time and Power Supply Ramping
```

Restore 1

```
# Run
./simv -ucli -do vcs_restore.ucli -l simv_restore.log
```

```
run_restore.csh | vcs_restore.ucli
dump -file xavcsmx.vpd -type vpd
dump -autoflush on -fid VPD0
dump -add * -depth 4
restore save_start
force snps_sptop.xil.SEL 01
run 15us
save sim_read1
```

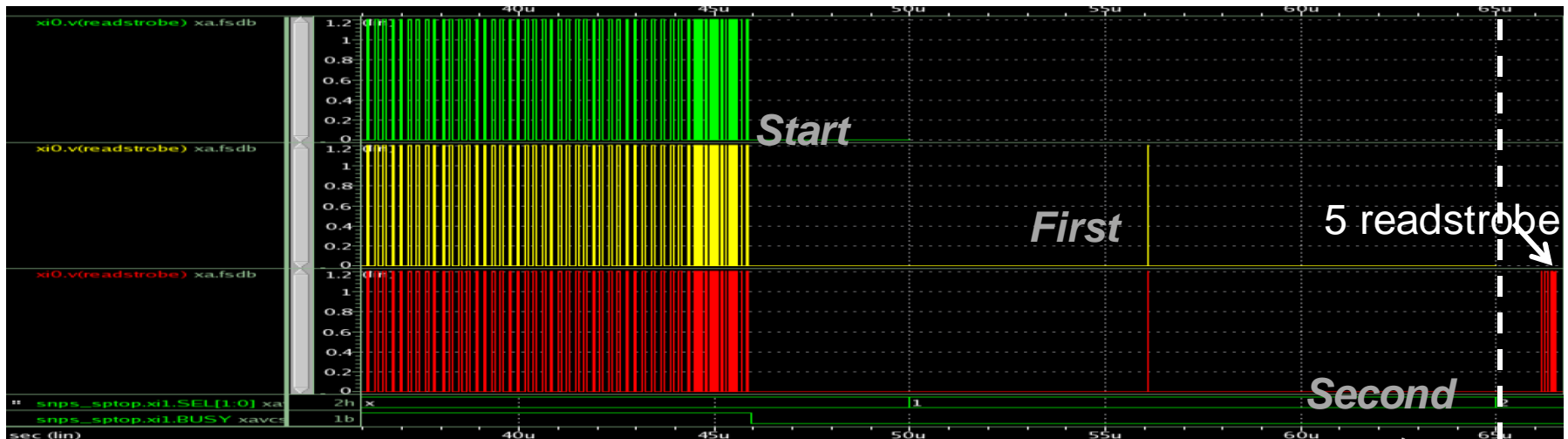
Restore_2

```
# Run
./simv -ucli -do vcs_restore_2.ucli -l simv_restore.log
```

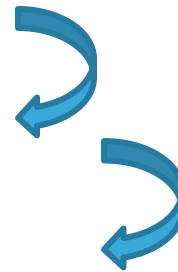
```
dump -file xavcsmx.vpd -type vpd
dump -autoflush on -fid VPD0
dump -add * -depth 4
restore sim_read1
force snps_sptop.xil.SEL 10
run 20us
quit
```

Save and Restore - Simulation Results

61



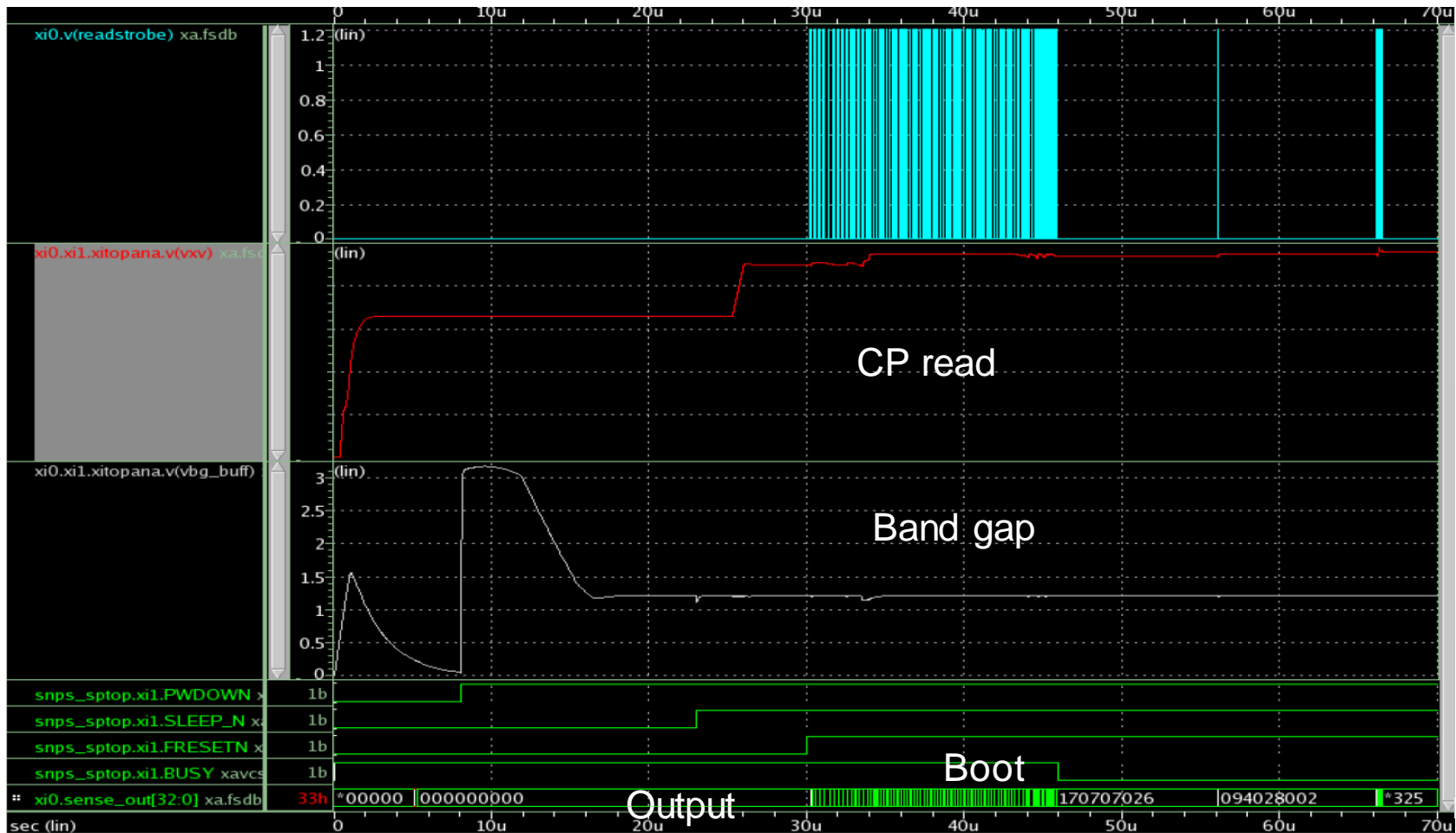
- Power up simulation takes 1h 30m
- Read operation takes 10m
- Power up + first read operation = 1h 40m



- ✓ With the Save and Restore capability in this case we save 1h 30m at the first operation then we save 1h 40m at the second operation, and so on...
- ✓ With more complex operations like program and erase we can save much more time

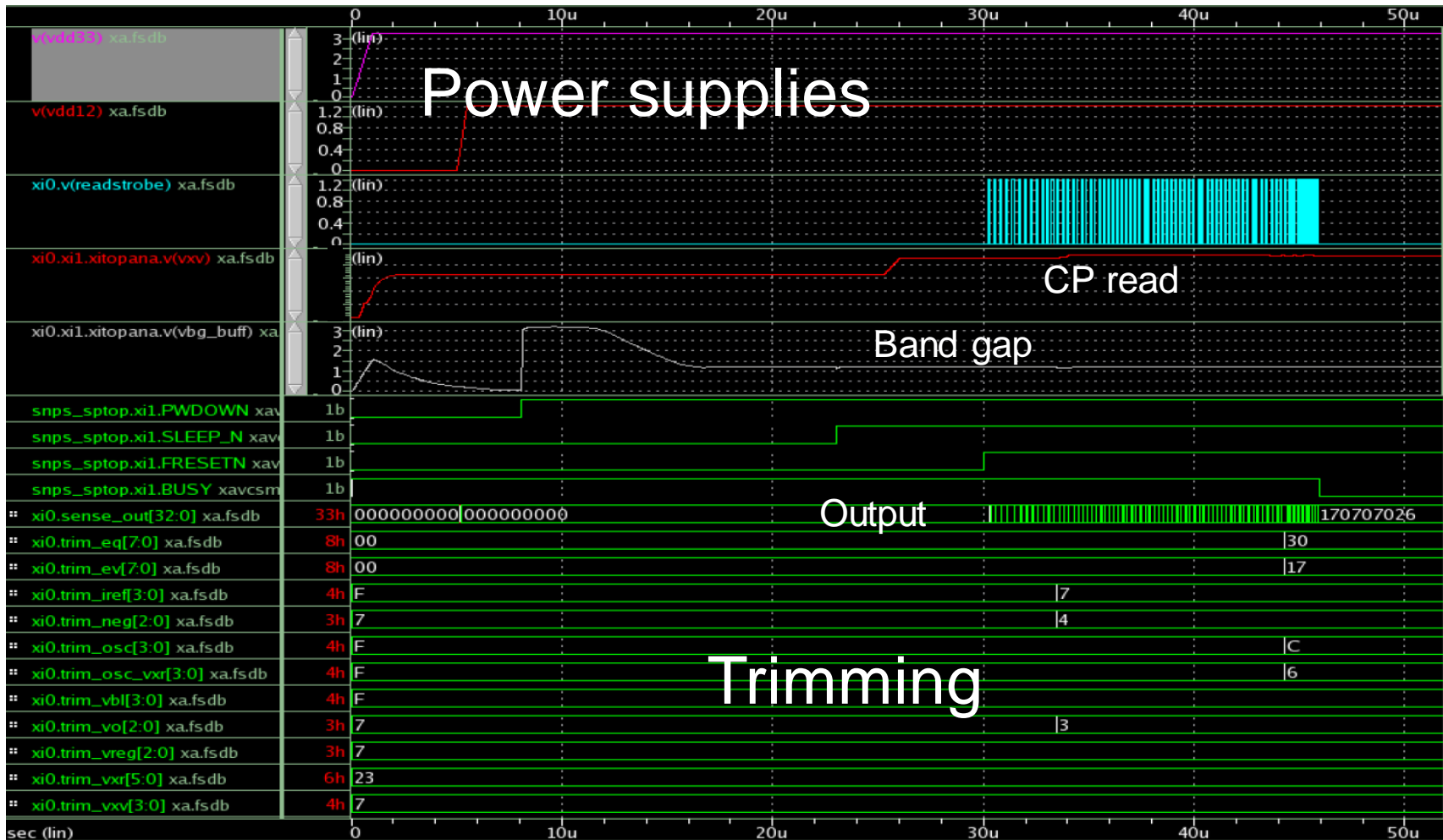
Power-up & Multiple Read Operations

62



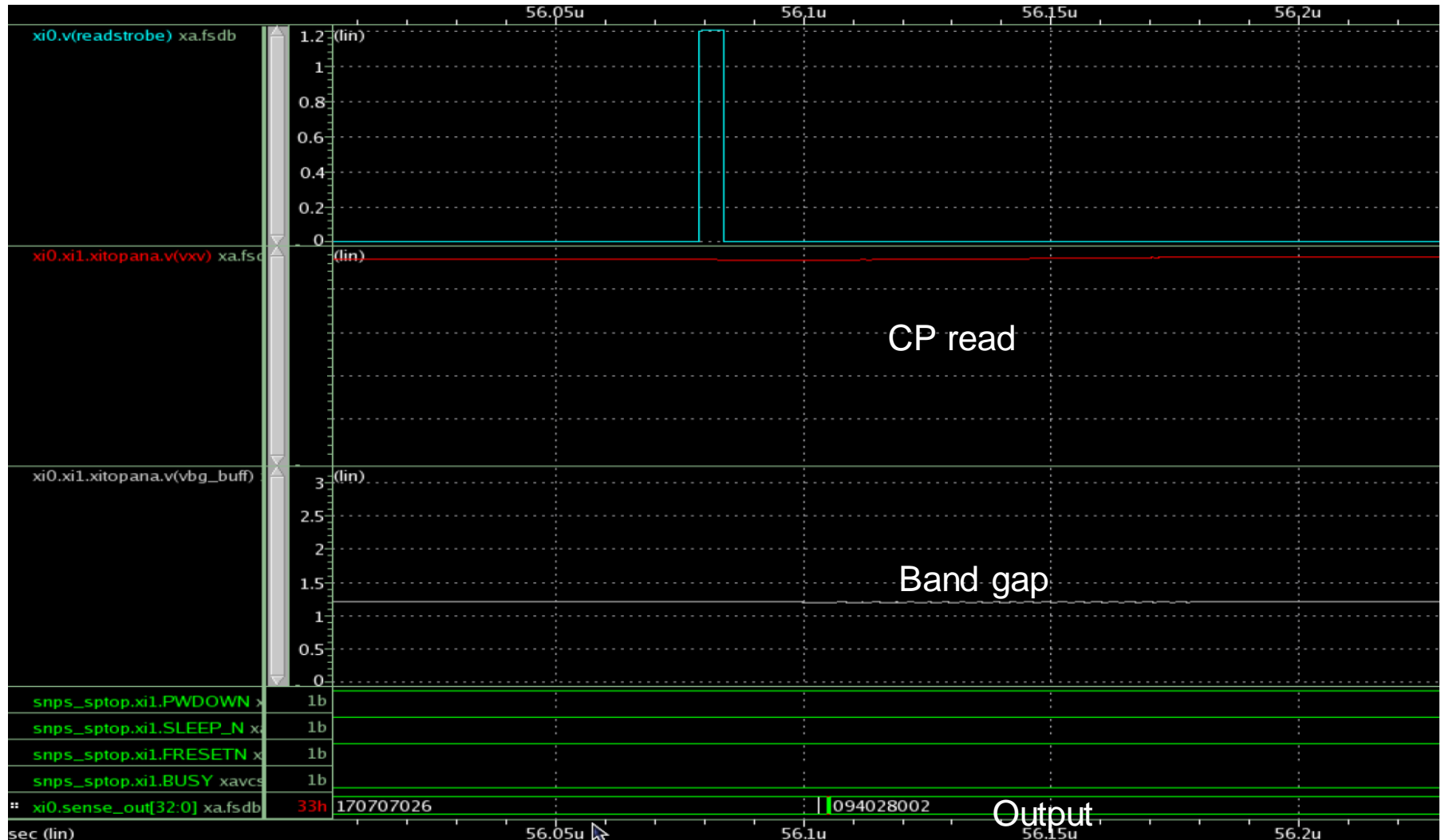
Power-up Details

63



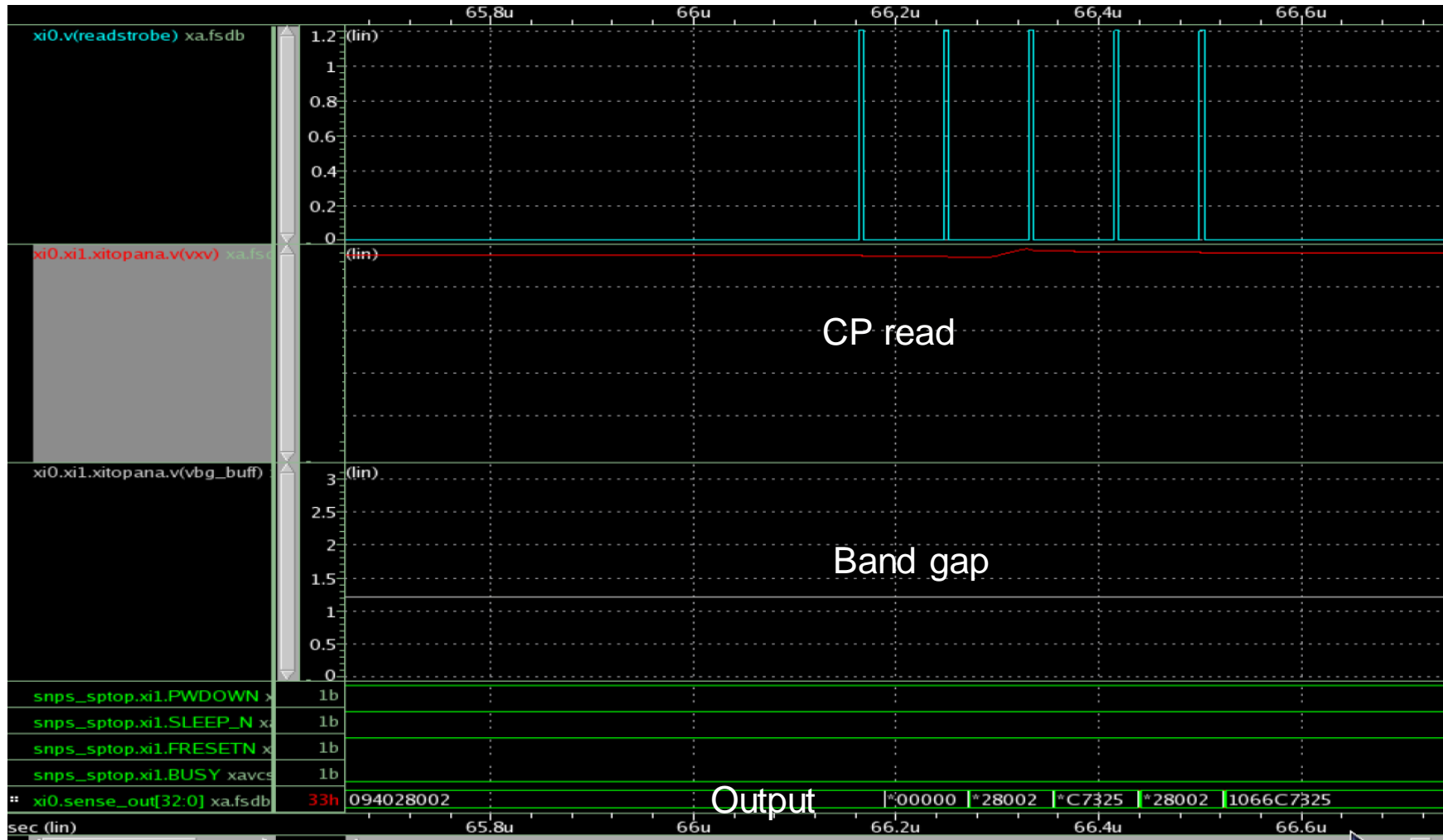
First Read Operation After Boot

64



Five Further Reads After Save & Restore

65



- **Synopsys VCS AMS meets ST needs for AMS design verification**
 - Fastest solution, accurate and easy to set up
 - Reliable
 - Valuable support from applications engineers
 - Collaboration with Synopsys expected soon to address GUI improvements
- **Unique features to speed up the whole design cycle**
 - Assertions to monitor analog to digital communication and prevent design failures
 - Save and restore (multi-scenario verification increases coverage)

Thank You

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Behavioral modelling of Analog-on-Top Mixed-Signal ICs

Gernot Koch

DVCon, Munich, October 14th, 2014

Micronas at a glance



Known and recognized in the **automotive** and **industrial** business as a reliable global partner for **intelligent, sensor-based system solutions**

About **900** employees worldwide

Leading **supplier** of **hall sensors** for the **automotive** industry

Core business **Automotive**

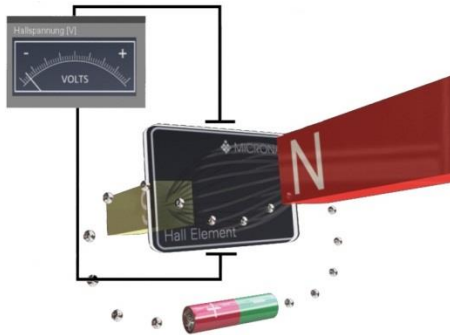
Focus on **sensors** and **sensor-based solutions**

Full in-house production with own **waferfab** and **backend operations** including testing and packaging

zero ppm quality to ensure **customer** satisfaction

Commitment to **environmental** protection

Hall sensors



Switches
(buckle, etc.)

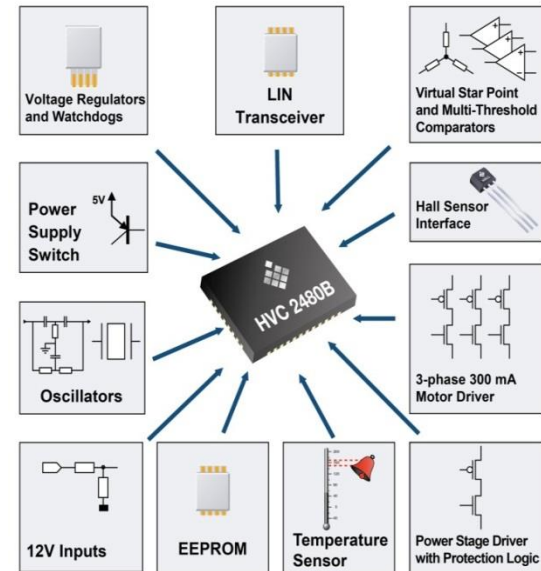


Linear, angular
(steering wheel)



Current sensor
(power module)

HV controllers

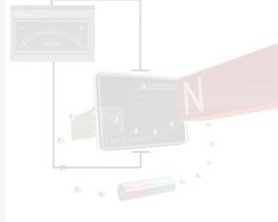
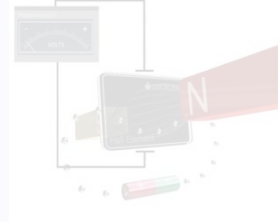


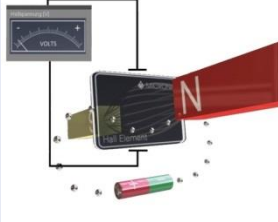
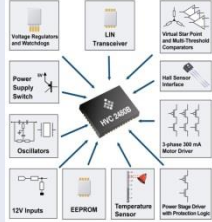


Fans



Actuators

Toplevel Simulation Strategy

Simulation style	Speed	Accuracy	Applied to
Full Spice	--	++	
Verilog / Spice	-	++	 
Verilog / VerilogA(MS)	0	0	
Discrete Real-type	++	-	 

Discrete Real-Type

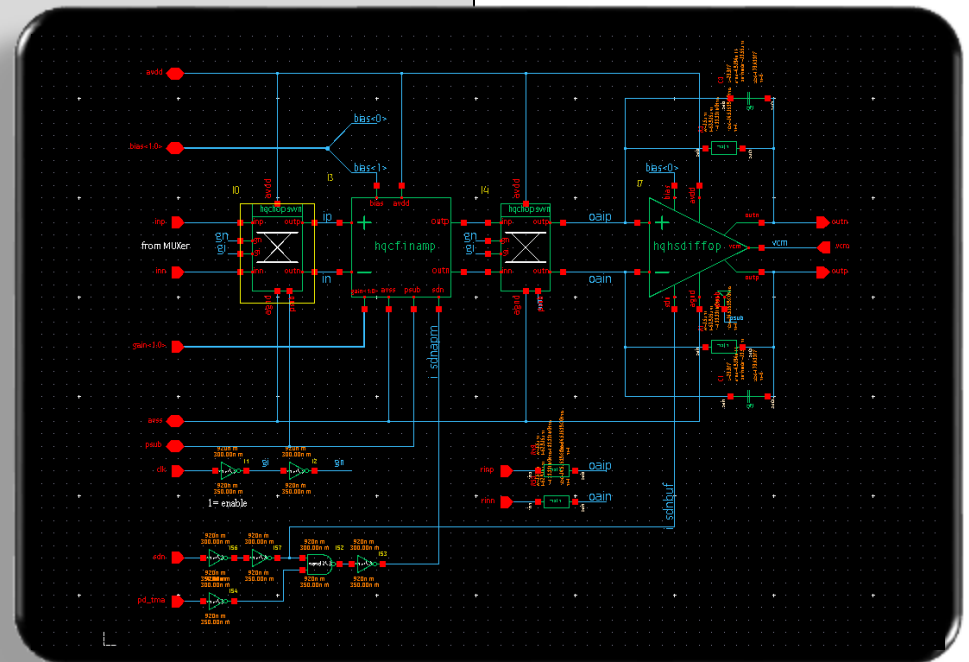
- ◆ Pure digital simulation (Verilog)
- ◆ Analog behavior modeled with real values (analogy: wreal)



Time discrete
Value continuous

Example: Difference amplifier w/ programmable gain

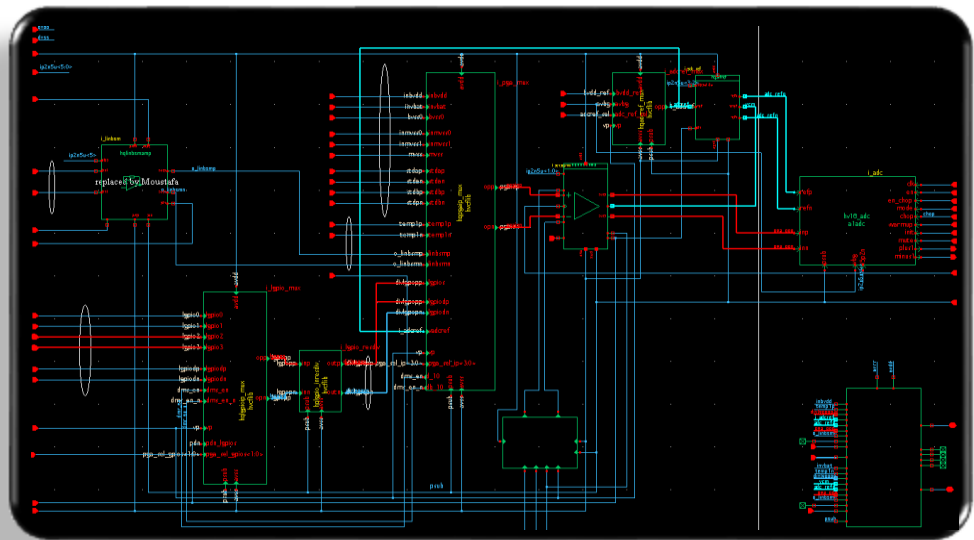
```
always @(r_inp or r_inn or r_vcm or r_rinp or r_rinn or gain) begin
    if (gain == 3)
        abs_gain = 4.0;
    else if (gain == 2)
        abs_gain = 10.0;
    else if (gain == 1)
        abs_gain = 20.0;
    else
        abs_gain = 40.0;
    oaip = r_inp * abs_gain + r_rinp;
    oain = r_inn * abs_gain + r_rinn;
    if (r_vcm + (oaip - oain)/2.0 < r_avdd)
        r_outp = r_vcm + (oaip - oain)/2.0;
    else
        r_outp = r_avdd;
    if (r_vcm - (oaip - oain)/2.0 > 0.0)
        r_outn = r_vcm - (oaip - oain)/2.0;
    else
        r_outn = 0.0;
end
```



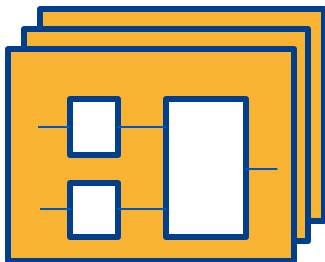
Netlisted topology

Design database

Schematic hierarchy (OA):



Representations (Views):



Schematic
Verilog
...

Requirements

- ◆ Netlisted hierarchy
 - ▶ No out-of-sync problems
 - ▶ Only one master
 - ▶ Minimized modeling effort

- ◆ Netlisted languages
 - ▶ SPICE
 - ▶ Verilog

Netlisted topology

```

module hqtswik (g, gn, i, o, psub, vdd, vp, vss);
input g;
input gn;
input i;
output o;
input psub;
input vdd;
input vp;
input vss;

wire node;

real r_i, r_o;

tranif1 (i, node, g);
cmos (o, node, g, gn);
rnmos (node, vp, gn);

initial
begin
    $xana_sink (i, r_i);
    $xana_source (o, r_o);
end

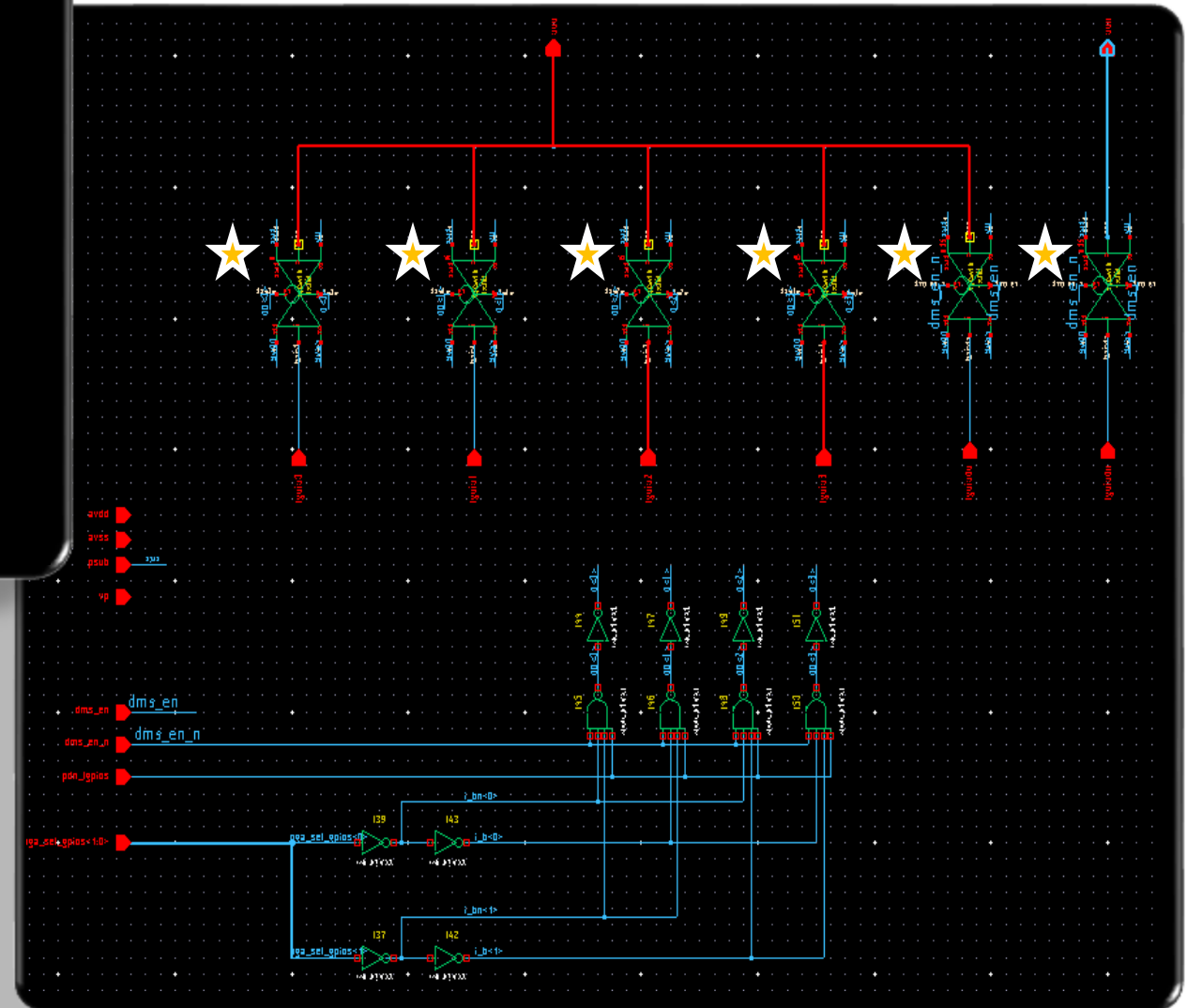
always @(r_i or g or gn) begin
    if (gn)
        r_o = 0.0;
    else if (g)
        r_o = r_i;
end

endmodule

```

★ Model

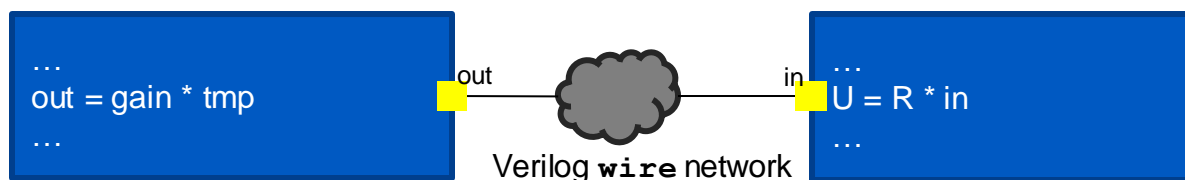
▲ Model contained



- ◆ reuse of topology
 - ▶ 1 cell altered
- ◆ schematic logic retained & verified

Discrete Real-type (DRT) modelling

- ◆ **Signal flow:** Verilog wire to transports non-logic values



Netlisting



- ◆ **Reciprocity:** Bi-directional transport

- ◆ Verilog wire transports composite values
- ◆ Direction configured separately for each component
- ◆ Needed to model e.g. a LIN phy

Distributed
Ohm's law



- ◆ **Duality:** Verilog wire still transports digital values

Mixed digital
and analog



Micronas custom PLI:
\$XANA

SystemVerilog extension in
VCS: **-xlmr coerce_nettype**

Signal flow

Wire type definition:

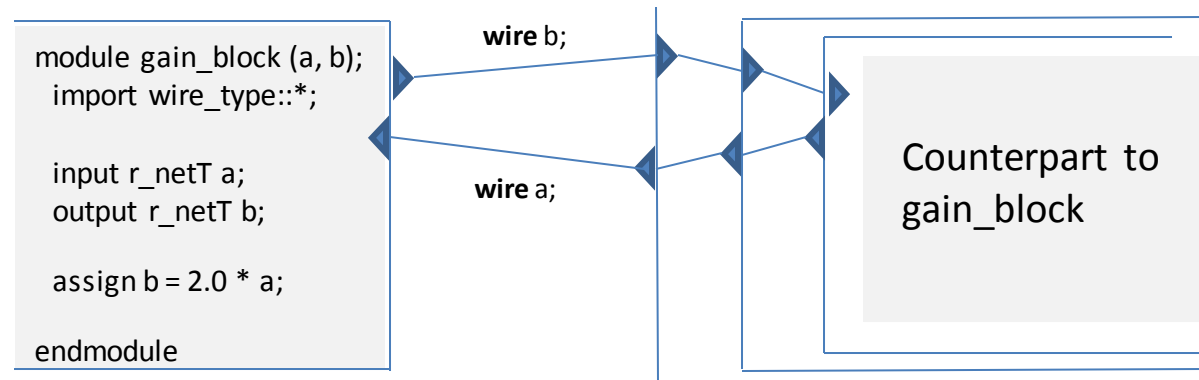
```
package wire_type;

nettype real r_netT with r_res;

function automatic real r_res (input real drivers []);
    r_res = 0.0;
    foreach (drivers[k]) r_res += drivers[k];
endfunction

endpackage
```

Models &
hierarchy



Enabled by vendor specific extension:

VCS: -xlm coerce_nettype

SV type 'interconnect' is similar, but requires netlister / code change

Reciprocity

E.g. LIN interface

- overcurrent
- standby
- ...

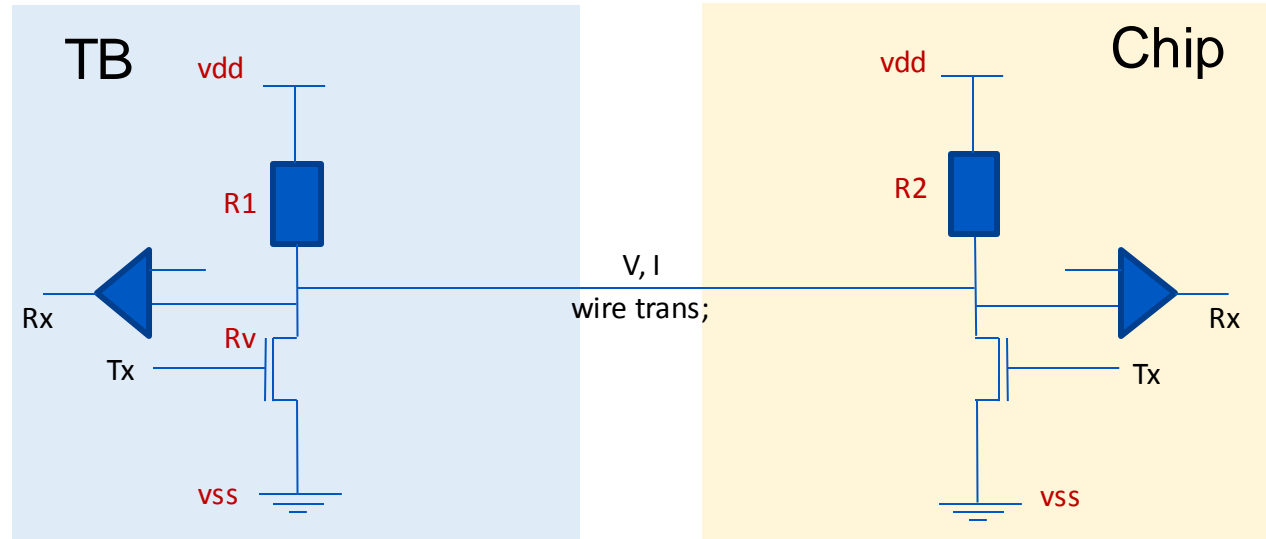
```
package wire_type;
```

```
typedef struct {
    real R1,Rv, V, I;
} viT;
```

```
nettype viT vi_netT with vi_res;
```

```
function automatic viT vi_res (
    input viT drivers []);
    vi_res = '{0.0, 0.0, 0.0, 0.0};
    foreach (drivers[k]) begin
        vi_res.R1 += drivers[k].R1;
        vi_res.Rv += drivers[k].Rv;
        vi_res.V += drivers[k].V;
        vi_res.I += drivers[k].I;
    end
endfunction
```

```
endpackage
```



$R1, Rv \rightleftharpoons V, I$

```
module TB (trans);
    import wire_type::*;
    inout vi_netT trans;
    ...
    parameter r1 = 10.0;
    // check V, I, calc Rv based on Tx&R1
    ...
    assign trans = '{R1, Rv, 0.0, 0.0};
endmodule
```

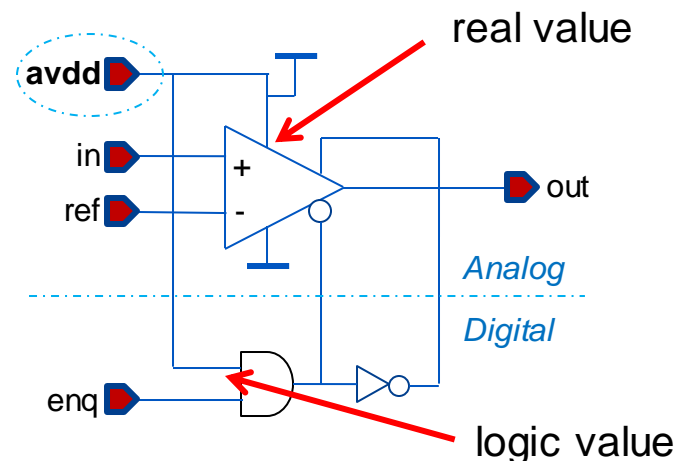
```
module Chip (trans);
    import wire_type::*;
    inout vi_netT trans;
    ...
    parameter r2 = 10.0
    // calc V, I, based on R2,R1,Rv,Tx
    ...
    assign trans = '{0.0, 0.0, V, I};
endmodule
```

Duality

- ◆ nets transporting real values may also need to transport verilog logic values

- ◆ e.g **avdd**

- ▶ stimuli for Analog & Digital domains



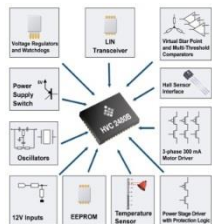
- ▶ amplifier output out limited by avdd value & avdd is logic 1 for enable logic in schematic

- ◆ very useful for power-up mode analysis

Not yet possible with off-the-shelf simulators
Requires custom PLI

Summary, Results

Run times:



Realtime μ C-S/W @20MHz	570 μ s
Discrete Real-Type models	2.8s
VerilogAMS behavioral models	354s
Verilog SPICE (single threaded)	25.5h

VCS

VCS-AMS

Modeling effort:

ADC with netlisted topology	2 days
ADC from scratch (no netlisting)	14 days

Common testbench:

- ◆ Netlisted topology allows testbench re-use for all configurations
- ◆ A few tricks allow the same simulation scenario to be applied to all configurations



Scenarios can be developed with fast turnaround using DRT models and then applied to all configurations

Questions

Thank you !